

BS EN 62341-6-2:2012



BSI Standards Publication

# Organic light emitting diode (OLED) displays

Part 6-2: Measuring methods of visual quality and ambient performance

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Published by BSI Standards Limited 2012

ISBN 978 0 580 67198 2

ICS 31.260

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 April 2012.

**Amendments issued since publication**

| <b>Amd. No.</b> | <b>Date</b> | <b>Text affected</b> |
|-----------------|-------------|----------------------|
|-----------------|-------------|----------------------|

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**Organic light emitting diode (OLED) displays -  
Part 6-2: Measuring methods of visual quality and ambient performance  
(IEC 62341-6-2:2012)**

Afficheurs à diodes électroluminescentes organiques (OLED) -  
Partie 6-2: Méthodes de mesure de la qualité visuelle et des caractéristiques de fonctionnement sous conditions ambiantes  
(CEI 62341-6-2:2012)

Anzeigen mit organischen Leuchtdioden (OLEDs) -  
Teil 6-2: Messverfahren für Bildqualität und Umgebungsbetriebseigenschaften  
(IEC 62341-6-2:2012)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

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## Foreword

The text of document 110/338/FDIS, future edition 1 of IEC 62341-6-2, prepared by IEC TC 110, "Flat panel display devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62341-6-2:2012.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2012-11-28
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2015-02-28

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**Annex ZA**  
(normative)**Normative references to international publications  
with their corresponding European publications**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

| <u>Publication</u> | <u>Year</u> | <u>Title</u>  | <u>EN/HD</u> | <u>Year</u> |
|--------------------|-------------|---|--------------|-------------|
| IEC 60050          | Series      | International electrotechnical vocabulary   | -            | -           |
| IEC 60081          | -           | Double-capped fluorescent lamps -<br>Performance specifications   | EN 60081     | -           |
| IEC 61966-2-1      | -           | Multimedia systems and equipment - Colour<br>measurement and management -<br>Part 2-1: Colour management - Default RGB<br>colour space - sRGB | EN 61966-2-1 | -           |
| IEC 62341-1-2      | -           | Organic light emitting diode displays -<br>Part 1-2: Terminology and letter symbols   | EN 62341-1-2 | -           |
| CIE 15             | 2004        | Colorimetry   | -            | -           |

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## ORGANIC LIGHT EMITTING DIODE (OLED) DISPLAYS –

### Part 6-2: Measuring methods of visual quality and ambient performance

#### 1 Scope

This part of IEC 62341 specifies the standard measurement conditions and measurement methods for determining the visual quality and ambient performance of organic light-emitting diode (OLED) display modules and panels. This document mainly applies to colour display modules.

#### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050 (all parts), *International Electrotechnical Vocabulary*  
(available at <<http://www.electropedia.org>>)

IEC 60081, *Double-capped fluorescent lamps – Performance specifications*

IEC 61966-2-1, *Multimedia systems and equipment – Colour measurement and management – Part 2-1: Colour management – Default RGB colour space – sRGB*

IEC 62341-1-2, *Organic light emitting diode displays – Part 1-2: Terminology and letter symbols*

CIE 15:2004, *Colorimetry*

#### 3 Terms, definitions and abbreviations

For the purposes of this document, the terms, definitions and abbreviations given in IEC 62341-1-2 and IEC 60050-845:1987 as well as the following apply.

##### 3.1 Terms and definitions

###### 3.1.1

###### visual inspection

a means for checking image quality by human visual observation for classification and comparison against limit sample criteria

###### 3.1.2

###### subpixel defect

for colour displays, all or part of a single subpixel, the minimum colour element, which is visibly brighter or darker than surrounding subpixels of the same colour. They are classified depending on the number and configuration of multiple subpixel defects within a region of the display



### **3.1.3**

#### **dot defect**

for monochromatic displays, all or part of a single subpixel, the minimum dot element, which is visibly brighter or darker than surrounding dots. They are classified depending on the number and configuration of multiple subpixel defects within a region of the display

### **3.1.4**

#### **bright subpixel defect**

subpixels or dots which are visibly brighter than surrounding subpixels of the same colour when addressed with a uniform dark or grey background

### **3.1.5**

#### **dark subpixel defect**

subpixels or dots are visibly darker than surrounding subpixels of the same colour when addressed with a uniform bright background (e.g. > 50 % full screen luminance)

### **3.1.6**

#### **partial subpixel defect**

subpixel or dot with part of the emission area obscured such that a visible difference in brightness is observed in comparison with neighbouring subpixels of the same colour

### **3.1.7**

#### **clustered subpixel defects**

subpixel or dot defects gathered in specified area or within a specified distance. Also known as “close subpixel defect”

### **3.1.8**

#### **unstable subpixel**

subpixel or dot that changes luminance in an uncontrollable way

### **3.1.9**

#### **pixel shrinkage**

reduction in the active emissive area of one or more subpixels (or dots) over time

### **3.1.10**

#### **panel edge shrinkage**

reduction in the active emissive area from the edges of the display area over time

### **3.1.11**

#### **line defect**

vertical or horizontal bright or dark line parallel to a row or column observed against a dark or bright background, respectively

### **3.1.12**

#### **bright line defect**

a line appearing bright on a screen displaying a uniform dark or grey pattern

### **3.1.13**

#### **dark line defect**

a line appearing dark when displayed with a uniform bright or grey pattern

### **3.1.14**

#### **mura**

region(s) of luminance and colour non-uniformity that generally vary more gradually than subpixel level defects. For classification, the maximum dimension should be less than one fourth of the display width or height

### **3.1.15**

#### **line mura**

variation in luminance consisting of one or more lines extending horizontally or vertically across all or a portion of the display (such as may be caused by TFT threshold voltage variation from laser induced crystallization)

### **3.1.16**

#### **colour mura**

mura that appears primarily in only one colour channel and results in a local variation of the white point (or CCT)

### **3.1.17**

#### **spot mura**

region of luminance variation larger than a single pixel appearing as a localized slightly darker or brighter region with a smoothly varying edge

### **3.1.18**

#### **stain mura**

region of luminance variation larger than a single pixel appearing as clearly defined edge bordering a region of brighter or darker luminance than surrounding regions

### **3.1.19**

#### **mechanical defects**

image artefacts arising from defects in protective and contrast enhancement films, coatings, mechanical fixturing, or other elements within in the active area of the display

### **3.1.20**

#### **scratch defect**

defect appearing as fine single or multiple lines or scratches, generally light in appearance on a dark background, and independent of display state

### **3.1.21**

#### **dent defect**

localized spot generally white or grey in appearance on dark background and independent of display state

### **3.1.22**

#### **foreign material**

defect caused by foreign material like dust or thread in between contrast enhancement films, protective films, or on emitting surface within the active area of the display

### **3.1.23**

#### **bubble**

defect caused by a cavity in or between sealing materials, adhesives, contrast enhancement films, protective films, or any other films within the visible area of the display

### **3.1.24**

#### **ambient contrast ratio**

contrast ratio of a display with external natural or artificial illumination incident onto its surface

NOTE Includes indoor illumination from luminaires, or outdoor daylight illumination.

### **3.1.25**

#### **colour gamut boundary**

surface determined by a colour gamut's extremes

### 3.1.26

#### **colour gamut volume**

a single number for characterizing the colour response of a display device in a three-dimensional colour space

NOTE Typically the colour gamut volume is calculated in the CIELAB colour space.

### 3.1.27

#### **ambient colour gamut volume**

number for characterizing the colour response of a display device, under a defined ambient illumination condition, in a three-dimensional colour space

NOTE Typically the colour gamut volume is calculated in the CIELAB colour space.

## 3.2 Abbreviations

|        |   |
|--------|---|
| CCT    | correlated colour temperature   |
| CIE    | International Commission on Illumination (Commission internationale de l'éclairage) |
| CIELAB | CIE 1976 (L*a*b*) colour space  |
| DUT    | device under test   |
| HD     | high definition   |
| ISO    | International Organization for Standardization                                      |
| LED    | light emitting diode  |
| LMD    | light measuring device  |
| LTPS   | low temperature polysilicon   |
| OLED   | organic light emitting diode  |
| PL     | photoluminescence   |
| QVGA   | quarter video graphics array  |
| RGB    | red, green, blue  |
| SDCM   | standard deviation of colour matching   |
| sRGB   | a standard RGB colour space as defined in IEC 61966-2-1                             |
| TFT    | thin film transistor  |
| TV     | television  |
| UV     | ultraviolet   |

## 4 Structure of measuring equipment

The system diagrams and/or operating conditions of the measuring equipment shall comply with the structure specified in each item.

## 5 Standard measuring conditions

### 5.1 Standard measuring environmental conditions

Electro-optical measurements and visual inspection shall be carried out under the standard environmental conditions, using at a temperature of  $25\text{ °C} \pm 3\text{ °C}$ , a relative humidity of 25 % to 85 %, and pressure of 86 kPa to 106 kPa. When different environmental conditions are used, they shall be noted in the visual inspection or ambient performance report.

## 5.2 Standard lighting conditions

### 5.2.1 Dark-room conditions

The luminance contribution from the background illumination reflected off the test display shall be  $\leq 0,01 \text{ cd/m}^2$  or less than 1/20 the display's black state luminance, whichever is lower. If these conditions are not satisfied, then background subtraction is required and it shall be noted in the ambient performance report. In addition, if the sensitivity of the LMD is inadequate to measure at these low levels, then the lower limit of the LMD shall be noted in the ambient performance report.

NOTE Unless stated otherwise, the standard lighting conditions shall be the dark-room conditions.

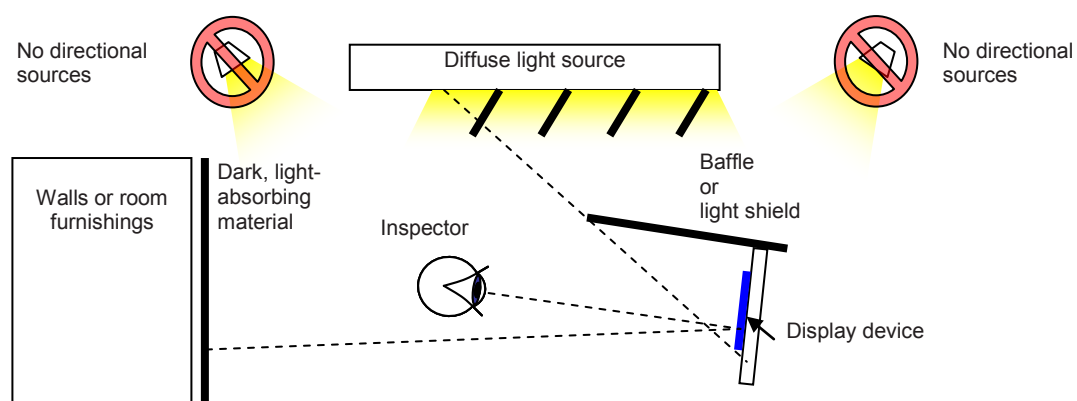
### 5.2.2 Ambient illumination conditions

#### 5.2.2.1 Ambient illumination conditions for visual inspection

Ambient lighting conditions have a strong impact on the ability of the inspector to resolve defects and large variations of light intensity in the visual field can lead to inspector fatigue and a resulting loss of sensitivity to defects. Refer to ISO 9241-310 for general guidance on optimal illumination conditions for visual inspection of pixel defects [1]<sup>1</sup>.

For inspector comfort and consistency of inspection conditions an average ambient illuminance of between 50 lx and 150 lx is suggested in the inspector's work area. This ambient illuminance may be measured, for example, with an illuminance meter facing directly upward in a horizontal plane at the approximate eye level of the inspector. Care shall be taken to use diffuse illumination, and diffuse textures in the inspection environment, to avoid glare in the visual field of the inspector.

As shown in Figure 1, the display under test shall be placed to avoid direct illumination from ambient room light sources. In addition, dark light-absorbing materials shall be used to cover specular surfaces that may be viewed by the inspector in direct reflection from the display surface. In any case, to limit degradation of the display contrast from ambient light, the ambient illuminance incident from room light sources on the display surface measured with the display off shall be  $< 20 \text{ lx}$ . If ambient illuminance at the display surface is  $> 20 \text{ lx}$ , it shall be noted in the visual inspection report.



IEC 84/12

**Figure 1 – Example of visual inspection room setup for control of ambient room lighting and reflections**

<sup>1</sup> Numbers in square brackets refer to the Bibliography.

### 5.2.2.2 Ambient illumination conditions for electro-optical measurements

The following illumination conditions are prescribed for electro-optical measurements of displays in ambient indoor or outdoor illumination conditions. Ambient indoor room illumination, and outdoor illumination of clear sky daylight, on a display shall be approximated by the combination of two illumination geometries [ 2 ]. Uniform hemispherical diffuse illumination will be used to simulate the background lighting in a room, or the hemispherical skylight incident on the display, with sun occluded. A directed source in a dark room will simulate the effect of directional illumination on a display by a luminaire in a room, or from direct sunlight.

Some displays can emit photoluminescence (PL) when exposed to certain light. The relative impact of PL on the reflection measurement can be determined, and is described in Annex A. An illumination condition that causes a significant reflection measurement error due to the presence of PL should be treated carefully. If the same illumination spectral distribution and illumination/detection geometry is used for the reflection measurements, and the calculation of ambient contrast ratio and colour, then the PL can be incorporated into the reflection coefficients. However, if the illumination spectra used in the calculations is significantly different, then the reflected component must be measured separately from the PL component. The latter case is not addressed in this document.

The following illumination conditions shall be used to simulate indoor and outdoor display viewing environments:

#### *Indoor room illumination conditions:*

- Uniform hemispherical diffuse illumination – Use a light source closely approximating CIE Standard Illuminant A, CIE Standard Illuminant D65, or fluorescent lamp FL1 as defined in CIE 15. The use of an infrared-blocking filter is also recommended to minimize sample heating from the illuminants. The UV region ( $< 380$  nm) of all light sources shall be cut off. If FL1 is used as a light source, the chromaticity tolerance area of the lamp shall be less than 5 standard deviation of colour matching (SDCM, see IEC 60081). The fluorescent lamp shall be stabilized, for example, by ageing for 100 hours, and not used beyond 2 000 hours. Additional sources may also be used, depending on the intended application. For spectral measurements, if it can be demonstrated that the display does not exhibit significant PL ( $< 1$  % PL, see Annex A) for the selected reference source spectra, then a spectrally smooth broadband source (such as an approximation to CIE Standard Illuminant A) may be used to measure the spectral reflectance factor. Without significant PL, a measurement of the spectral reflectance factor using a broad source (like Illuminant A) enables the ambient contrast ratio and colour to be calculated later for the desired reference spectra (for example D65). The indoor room contrast ratio shall be calculated using 60 lx of hemispherical diffuse illumination (with specular included) incident on the display surface for a typical TV viewing room, and 300 lx for an office environment [3]. The actual hemispherical diffuse reflectance factor measurement may require higher illumination levels for better measurement accuracy. The results are then scaled to the required illumination levels.
- Directional illumination- The same source spectra shall be used as with hemispherical diffuse illumination. If a different spectral source is used, it shall be noted in the ambient performance report. The presence of significant PL (see Annex A) shall also be determined for the measured source, and the preceding limitations be applied when PL is present. The indoor room contrast ratio or colour shall be calculated using directional illumination of 40 lx incident on the display surface for a typical TV viewing room, and 200 lx for an office environment with the display in the vertical orientation. The actual reflectance factor measurement may require higher illumination levels for better measurement accuracy. The directed source shall be  $35^\circ$  above the surface normal ( $\theta_s=35^\circ$ ,  $\theta_d=0^\circ$ , see Figure 3) and have an angular subtense of no more than  $8^\circ$ . The angular subtense is defined as the full angle span of the light source from the centre of the display's measurement area.

NOTE Other illumination levels may be used in addition to those defined above for calculating the ambient contrast ratio under indoor illumination conditions. However, approximately 60 % of the total illuminance should be hemispherical diffuse, and 40 % directional illumination.

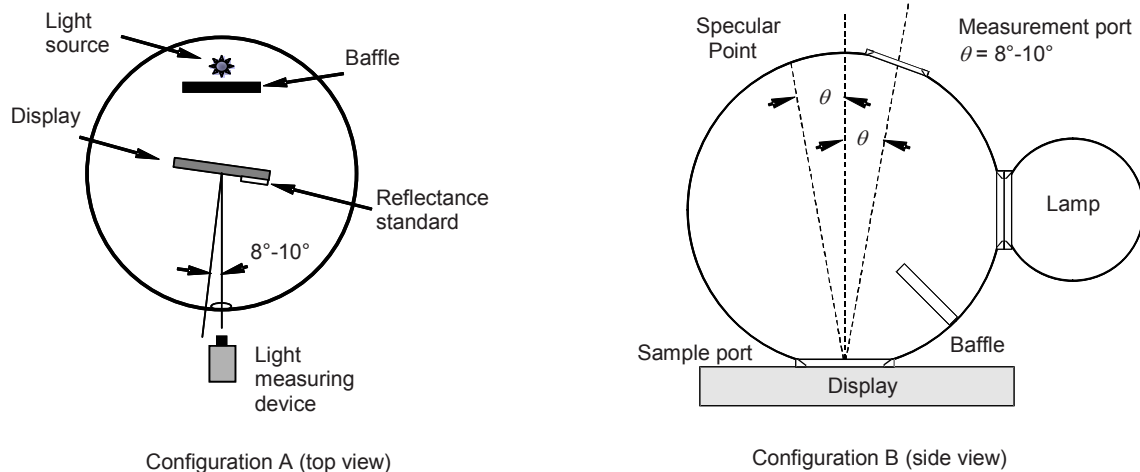
*Daylight illumination conditions:*

- Uniform hemispherical diffuse illumination – Use a light source closely approximating skylight with the spectral distribution of CIE Illuminant D75 [4]. Additional CIE daylight illuminants may also be used, depending on the intended application. An infrared-blocking filter is recommended to minimize sample heating. The UV region (< 380 nm) of the light source shall be cut off. For spectral measurements, if it can be demonstrated that the display does not exhibit significant PL for a 7 500 K correlated colour temperature (CCT) source, then spectral reflectance factor measurements can be made using a spectrally smooth broadband source (such as an approximation to CIE Standard Illuminant A). The contrast ratio or colour can be calculated later for the D75 Illuminant spectra. The daylight contrast ratio and colour shall be calculated using 15 000 lx of hemispherical diffuse illumination (with specular included) incident on a display surface in a vertical orientation [4, 5]. The actual hemispherical diffuse reflectance factor measurement may be taken at lower illumination levels.
- Directional illumination – The directional light source shall approximate CIE daylight Illuminant D50 [4]. Additional CIE daylight illuminants may also be used, depending on the intended application. The use of an infrared-blocking filter is recommended to minimize sample heating. The UV region (< 380 nm) of the light source shall be cut off. If it can be demonstrated that the display does not exhibit significant PL for a source approximating Illuminant D50, then a spectrally smooth broadband source (such as an approximation to CIE Standard Illuminant A) may be used for the reflectance factor measurement. The ambient contrast ratio or colour can be calculated later with the D50 Illuminant spectra. The daylight contrast ratio or colour shall be calculated using 65 000 lx for a directed source at an inclination angle of  $\theta_s = 45^\circ$  to the display surface (see Figure 3) [4],[5]. The actual reflectance factor measurement may be taken at lower illumination levels, and the contrast ratio and colour calculated for the correct illuminance. The directed source shall have an angular subtense of approximately  $0,5^\circ$ .

For daylight contrast ratio and colour calculations from spectral reflectance factor measurements, the relative spectral distributions of CIE Illuminant A, lamp FL1, D65, D50 and D75 tabulated in CIE 15 shall be used. Additional CIE daylight illuminants shall be determined using the appropriate eigenfunctions, as defined in publication CIE 15.

### 5.2.2.3 Uniform hemispherical diffuse illumination

An integrating sphere, sampling sphere, or hemisphere shall be used to implement uniform hemispherical diffuse illumination conditions. Two possible examples of the measurement geometry are shown in Figure 2. If an integrating sphere that is at least seven times the physical outer diagonal of the display is available, the display can be mounted in the centre of the sphere (Figure 2, configuration A). For large displays, a sampling sphere (configuration B) or hemisphere would be more suitable. In all cases, the configuration shall follow the standard  $di/8^\circ$  to  $di/10^\circ$  illumination/detection geometry, where  $di$  is the standard notation for diffuse.



IEC 85/12

**Figure 2 – Example of measurement geometries for diffuse illumination condition using an integrating sphere and sampling sphere**

- a) The display is placed in the centre of an integrating sphere/hemisphere, or against the sample port of a sampling sphere. The reflected luminance off the display from the sphere shall be much greater than the luminance from the display-generated light. For displays without significant PL, the reflected luminance from the sphere can be estimated with the display turned OFF.
- b) For daylight measurements with an approximate 7 500 K CCT light source, an infrared-blocking filter is recommended to minimize sample heating. The colour temperature and illumination spectra can be measured from the reflected light of a white diffuse reflectance standard near the display measurement area (Figure 2, Configuration A), or the sampling sphere wall adjacent to the sample port (Figure 2, Configuration B.). The type of light source used, and its CCT, shall be noted in the ambient performance report.
- c) The light measuring device (LMD) is aligned to view the centre of the display through a measurement port in the sphere wall at an  $8^\circ$  ( $-0^\circ$ ,  $+2^\circ$ ) angle from the display normal. The required LMD angle of inclination can also be realised by tilting the display within the integrating sphere. The LMD is focused on the display surface.
- d) The measurement port diameter shall be 20 % to 30 % larger than the effective aperture of the LMD lens. Care needs to be taken to avoid any direct light from the sources, or any bright reflections off any surface (other than the screen itself), from hitting the lens of the LMD in order to minimise veiling glare contamination of the reflected luminance measurement. The LMD shall be moved back from the hole so that the bright walls of the sphere are not visible to the LMD. In addition, the sample port diameter will typically need to be larger than 25mm in order for the luminance meter's or spectroradiometer's field of view to be completely contained within the sample port.
- e) The measurement port shall be bevelled away from the lens. The small diameter of the bevel is toward the LMD, and the large diameter on the inside of the sphere.
- f) The spectral irradiance or illuminance on the display can be measured using a white diffuse reflectance standard with known hemispherical diffuse spectral reflectance factor  $R(\lambda)$ , or the photopically-weighted (or luminous) hemispherical diffuse reflectance factor  $R$ . The white diffuse reflectance standard must be calibrated under uniform hemispherical diffuse illumination in an integrating sphere. When an integrating sphere (configuration A) or hemisphere is used, the white diffuse reflectance standard shall be placed on the display surface. If  $t$  is the thickness of the white diffuse reflectance standard, then it shall be placed on the surface a distance of  $5*t$  to  $7*t$  from the measurement area. The white reflectance standard can also be placed adjacent and in the same plane as the display if the sphere illumination is uniform over that distance. In the case of the sampling sphere, the spectral irradiance can be determined by a measurement of the interior sphere wall adjacent to the sample port.[6] The hemispherical diffuse spectral reflectance factor, or

the luminous hemispherical diffuse reflectance factor, of the interior sphere wall can be determined by comparing the spectral radiance (or luminance) of the wall with that of a calibrated white diffuse reflectance standard placed at the sample port (i.e.  $R_{\text{wall}} = R_{\text{std}} \cdot (L_{\text{wall}}/L_{\text{std}})$ ).

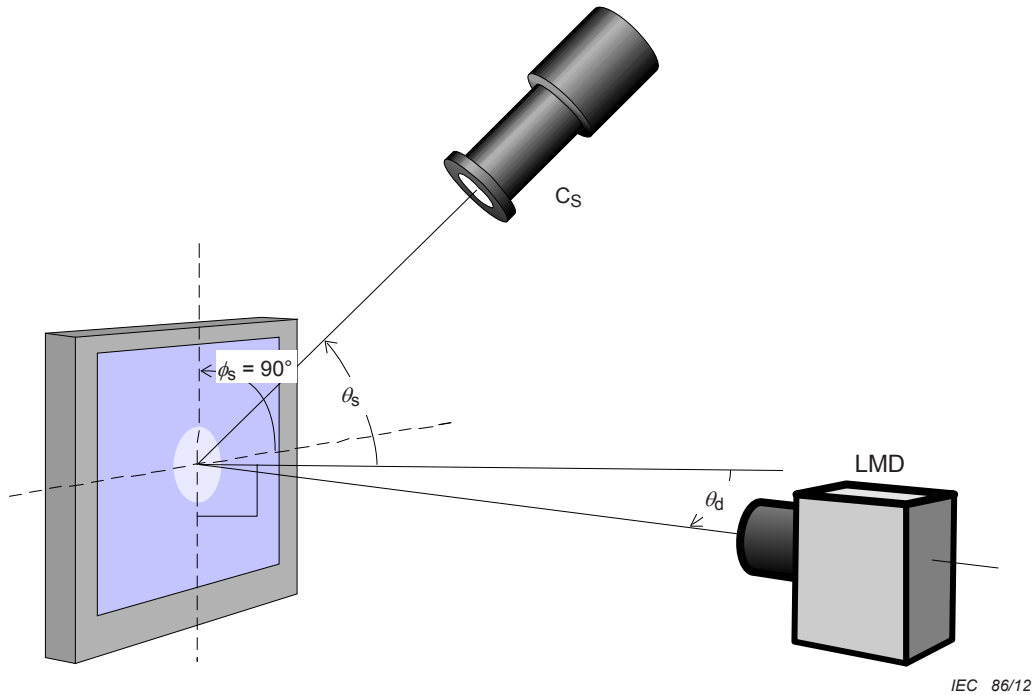
- g) If a sampling sphere is used, the display measurement area shall contain more than 500 display pixels. It is recommended that the sampling sphere be at least six times larger than the sample port diameter. If there is a significant distance between the display emitting surface and the sample port entrance, then the size of the sample port may need to be increased [7].
- h) The illuminance across the display measurement area shall vary less than  $\pm 5\%$  from the average.

#### 5.2.2.4 Directed source illumination

Directional illumination shall be simulated by an isolated directed source (Figure 3) at a defined angle of inclination to the display surface normal, or ring light (Figure 4) centred about the normal. This measurement shall be performed in a dark room, with all potential reflective room surfaces having a matt black coating. Light from the isolated directed source that is reflected off the display in the specular direction can be collected by a light trap to minimize its contribution to stray light contamination. The isolated directed source is the preferred directed source. If the display exhibits strong asymmetric scatter (matrix scatter [8]), then a ring light shall be used.

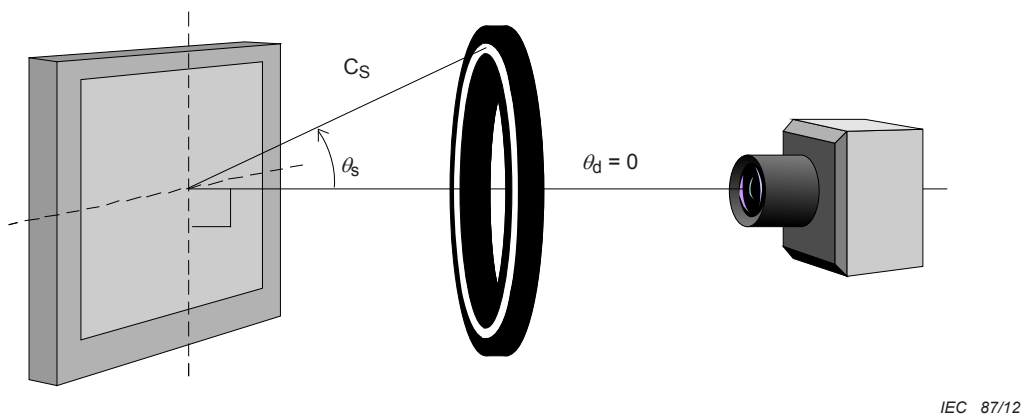
- a) Position the LMD normal ( $\theta_d = 0^\circ$ ) to the display, and focus on the display surface. The isolated directed light source is aligned in the same vertical plane ( $\phi_s = 0^\circ$ ) as the display normal and LMD, but at an inclination angle  $\theta_s$  from the horizontal plane. The distance between the display and directed source  $C_s$  can be adjusted so that the light source has an angular subtense of  $\leq 8^\circ$  for indoor applications, or approximately  $0,5^\circ$  angular subtense from the center of the display measurement area for outdoor applications. For ring light sources, a fibre-optic ring light shall be used, with an emitter angular subtense of approximately  $0,5^\circ$ . The ring light emitting plane must be co-planar with the display surface and centred about the measurement area. The inclination of the light  $\theta_s$  can be set by adjusting the ring light working distance to the display. The central clear aperture of the ring light shall be at least 30% larger than the effective aperture of the LMD lens. Additional source/detector geometries can be used, but shall be noted in the ambient performance report.
- b) The reflected luminance off the display from the directed source shall be much greater ( $> 10$ ) than the luminance from the display-generated light.
- c) The spectral irradiance or illuminance at the display measurement position can be determined by a white diffuse reflectance standard with a known spectral reflectance factor or photopically weighted (or luminous) reflectance factor. The white diffuse reflectance standard shall be placed at the same measurement position as the display, which may require the display to be moved away for the measurement of the white diffuse reflectance standard. The white diffuse reflectance standard must be calibrated at the same source-detector geometry as the display measurement. For photometric measurements, the white diffuse reflectance standard shall be calibrated with the same source spectral distribution that is to be used for the contrast calculation. The type of light source used, and its correlated colour temperature, shall be noted in the ambient performance report.
- d) The illuminance across the display measurement area shall vary less than  $\pm 5\%$  from the average.





NOTE The display may also be rotated  $90^\circ$  with the light source in the horizontal plane.

**Figure 3 – Directional source measurement geometry using an isolated source**



**Figure 4 – Directional source measurement geometry using a ring light source**

### 5.3 Standard setup conditions

#### 5.3.1 General

Standard setup conditions are given below. Any deviations from these conditions shall be noted in the ambient performance report.

#### 5.3.2 Adjustment of OLED display modules

The display luminance, contrast ratio, correlated colour temperature of the white point and other relevant parameters shall to be adjusted to nominal values, and shall be noted in detail on the ambient performance report. For a full colour display, white colour chromaticity shall also be adjusted to the nominal product design values. When there is no level specified, the maximum contrast or luminance level shall be used and the settings noted in the ambient performance report. These adjustments shall be held constant for all measurements, unless stated otherwise.

### 5.3.3 Starting conditions of measurements

Measurements shall be started after the OLED display modules and measuring instruments achieve stability. Sufficient warm-up time has to be allowed for the OLED display modules to reach a luminance stability level of less than  $\pm 5\%$  over the entire measurement for a given display image.

### 5.3.4 Conditions of measuring equipment

- a) The standard measurement setup is shown in Figure 5. The LMD must be a luminance meter, or a spectroradiometer capable of measuring spectral radiance over at least the 380 nm to 780 nm wavelength range, with a maximum bandwidth of 10 nm for smooth broadband spectra. For light sources that have sharp spectral features, like LEDs and fluorescent lamps, the maximum bandwidth shall be  $\leq 5$  nm. The spectral bandwidth of the spectroradiometer shall be an integer multiple of the sampling interval. For example, a 5 nm sampling interval can be used for a 5 nm or 10 nm bandwidth.

Care shall be taken to ensure that the device has enough sensitivity and dynamic range to perform the required task. The measured LMD signal shall be at least ten times greater than the dark level of the LMD.

- b) The light-measuring device shall be focused on the image plane of the display and aligned perpendicular to its surface, unless stated otherwise.
- c) The relative uncertainty and repeatability of all the measuring devices shall be maintained by following the instrument supplier's recommended calibration schedule.

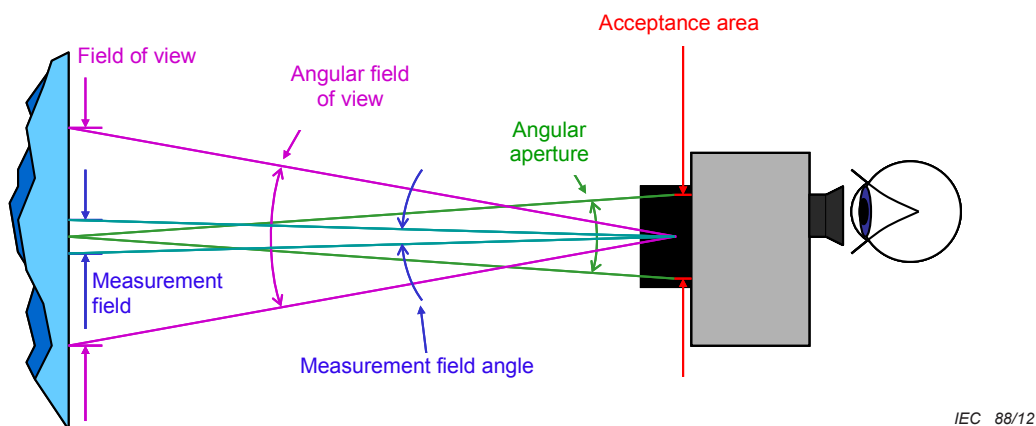


Figure 5 – Layout diagram of measurement set up

- d) The LMD integration time shall be an integer number of frame periods, synchronized to the frame rate, or the integration time shall be greater than two hundred frame periods.
- e) When measuring matrix displays, the light measuring devices shall be set to a measurement field that includes more than 500 pixels. If smaller measurement areas are necessary, equivalence to 500 pixels shall be confirmed.
- f) The standard measuring distance  $I_{x0}$  is  $2,5 \times V$  (for  $V \geq 20$  cm) or 50 cm (for  $V < 20$  cm), where  $V$  is the height of the display active area, or the shorter dimension of the active area. The measuring distance shall be noted in the ambient performance report.
- g) The angular aperture shall be less than or equal to  $5^\circ$ , and measurement field angle shall be less than or equal to  $2^\circ$  (Figure 5). The measuring distance and the aperture angle may be adjusted to achieve a measuring field greater than 500 pixels if setting the above aperture angle is difficult.
- h) Display modules shall be operated at their design field frequency. When using separate driving signal equipment to operate a panel, the drive conditions shall be noted in the ambient performance report.

## 6 Visual inspection of static images

### 6.1 General

In recent years, efforts have been made to utilize automated machine vision inspection as a means of detecting visual defects, but at this time a rigorous system to connect the human physiological response to measured quantities is not complete for all classes of defects. Therefore, human visual inspection and comparison against limit samples remains the most universal system for grading and classification of visual defects. For purposes of communicating failure modes and setting specification criteria a standard classification scheme and measurement method for visual inspection of OLED display panels and modules is needed.

### 6.2 Classification of visible defects

#### 6.2.1 Classification scheme

To aid in communicating and specifying visual defects, as well as in determining failure modes, it is useful to specify a classification scheme for visual defects. Figure 6 depicts a classification scheme. There are two general types of defects: those that depend on the electro-optical response and those that are mechanical in origin. Electro-optical defects are ordered from top to bottom based on the clarity of the defect edge typically observed. Mechanical defects generally originate from process damage or contamination.

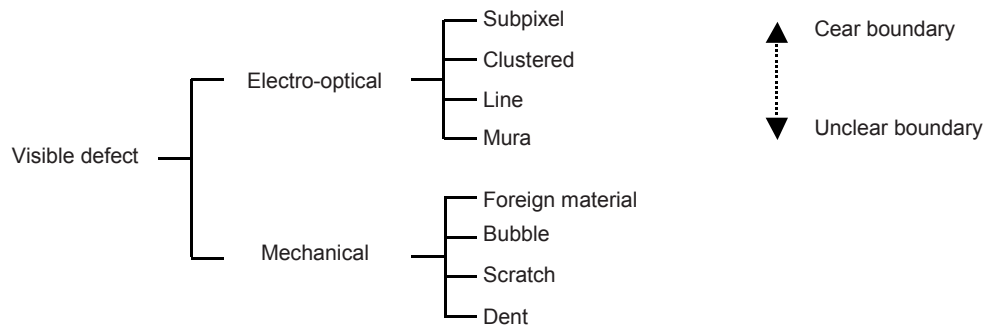


Figure 6 – Classification of visible defects

#### 6.2.2 Reference examples for subpixel defects

Figure 7a provides an example of one subpixel bright defect of red, green and blue, respectively. It should be understood that the defect designations described here apply to other subpixel arrangements that may be contemplated (for example inclusion of a white subpixel). Figure 7b shows examples of two adjacent bright subpixel defects connected or disconnected in horizontal and vertical orientation. Figure 7c shows examples of three adjacent bright subpixel defects connected in horizontal and vertical orientations.

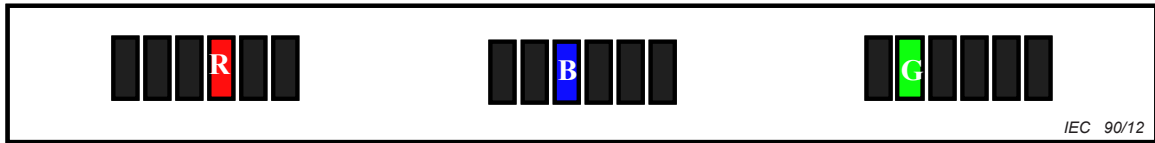


Figure 7a – Single bright subpixel defect

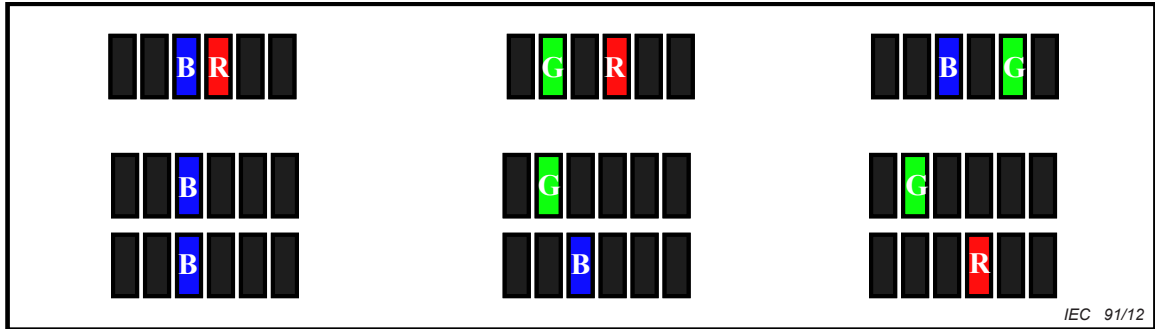


Figure 7b – Two adjacent bright subpixel defects

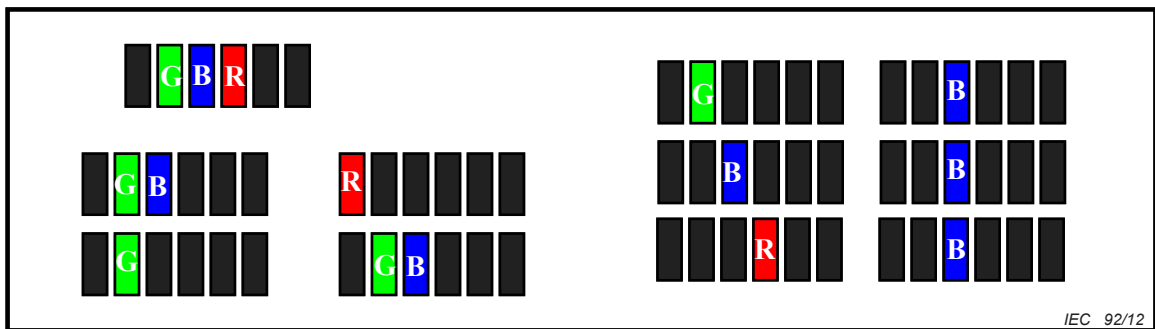
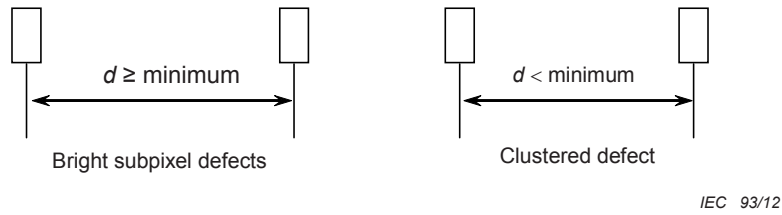


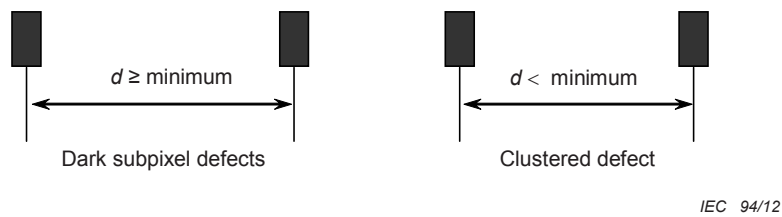
Figure 7c – Three adjacent bright subpixel defects

### Figure 7 – Bright subpixel defects

If multiple subpixel defects are a specified distance apart, they are classified as individual subpixel defects. If they occur within a specified distance they are classified as a close (or cluster) subpixel defect. Figures 8a and 8b depict the criteria for classifying bright and dark subpixel defects respectively, located within a minimum specified distance  $d$  as close subpixel defects. Note that the specified distance  $d$  applies to the separation between subpixels along any direction.



**Figure 8a – Bright subpixel criteria for clustered defect classification**

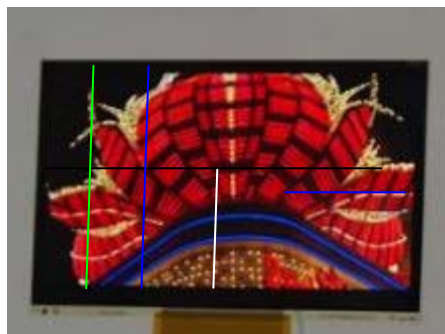


**Figure 8b – Dark subpixel to dark subpixel**

**Figure 8 – Criteria for classifying bright and dark subpixel defects**

### 6.2.3 Reference example for line defects

Line defects are evident as horizontal or vertical bright or dark lines extending partially or fully across the image and typically result from electrical shorts or disconnects. Figure 9 depicts an image with several bright and dark line defects.



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**Figure 9 – Bright and dark line defects**

### 6.2.4 Reference example for mura defects

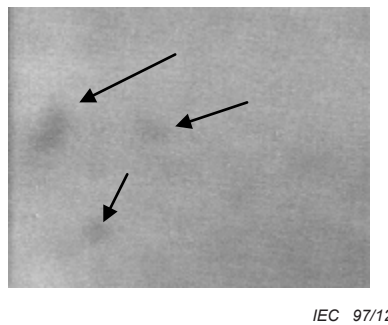
Mura defects comprise regions of luminance and colour non-uniformity that generally vary more gradually than subpixel level defects. The visibility of such defects is strongly dependent on the length scale of the defect as well as the local peak-to-peak luminance variation. Such features are visible for luminance variations as low as 1 % to 2 %. Typically the minimum width or height of such features is ~ 0,5 mm to 2 mm.

An example of a line mura defect resulting from non-uniform TFT characteristics for an OLED driven by an LTPS backplane is illustrated in Figure 10. Non-uniform lines run across the display when an image of a uniform white background is rendered on the display.



**Figure 10 – Sample image of line mura defect associated with TFT non-uniformity**

Non-uniform luminance variations with limited extent in both width and height are classified as spot mura. An example of a spot mura is illustrated in Figure 11. Line mura or spot mura defects that exhibit a non-uniformity in colour as well as luminance are classified as colour mura.



**Figure 11 – Example of spot mura defect in a grey background**

### **6.3 Visual inspection method and criteria**

#### **6.3.1 Standard inspection conditions**

##### **6.3.1.1 Environmental conditions**

Unless stated otherwise, the standard environmental conditions for visual inspection will be used.

##### **6.3.1.2 Ambient lighting conditions for visual inspection**

Unless stated otherwise, the standard ambient lighting conditions for visual inspection shall be used. Any deviation from these conditions shall be noted in the visual inspection report.

It is recognized that specific ambient lighting conditions may depend on the inspection purpose or intended application use for the OLED display panels or modules even though such conditions may not be optimal for inspector comfort or sensitivity to defects. Any deviation from the standard room lighting conditions shall be noted in the visual inspection report and shall include measurement of the illuminance normal to the display surface, average ambient illuminance of the inspector work area (as described in 5.2.2.1) and any other details relevant to the application environment such as the use of a dark room environment or direct illumination sources.

Lighting conditions shall be maintained during the inspector's session and from inspector to inspector. Inspectors should be adapted to the lighting conditions for a period of 10 min prior to beginning an inspection session.

### **6.3.1.3 Visual conditions**

#### **6.3.1.3.1 Viewing direction**

Visual inspection shall be conducted nominally viewing the display at normal incidence unless otherwise stated.

#### **6.3.1.3.2 Viewing distance**

The distance between OLED display panel or module and inspector's eyes shall be noted in the visual inspection report. Visual acuity of 1,0 corresponds to an ability of the inspector to resolve features of 0,3 mrad (1 arcmin) spacing. An optimal viewing distance,  $D_{opt}$  corresponding to twice the distance at which individual subpixels are resolved is recommended  $D_{opt} = 2 \times L / 0,3 \text{ mrad}$ , where  $L$  is the horizontal distance between subpixels. For example, a 2.2" (56 mm) diagonal QVGA (320 × 240) display with ~50 μm subpixel width is recommended to be viewed at 330 mm. For a 37" (940 mm) diagonal full HD display (1 920 × 1 080) with 140 μm subpixel width, the recommended viewing distance is 950 mm. The minimum viewing distance shall be 300 mm.

#### **6.3.1.4 Human inspection**

The inspector shall have normal colour vision and visual acuity (corrected to)  $\geq 1,0$  in decimal notation as determined by a qualified eye care professional or physician using methods consistent with those defined by the International Council on Ophthalmology.[9,10]. For colour vision, the Ishihara test is recommended and for visual acuity the Snellen test or Landolt C test is recommended.

### **6.3.1.5 Electrical driving condition**

#### **6.3.1.5.1 Driving condition of OLED display panels or modules**

Value of driving voltage shall be supplied on specification of OLED display panels or modules.

#### **6.3.1.5.2 Test pattern**

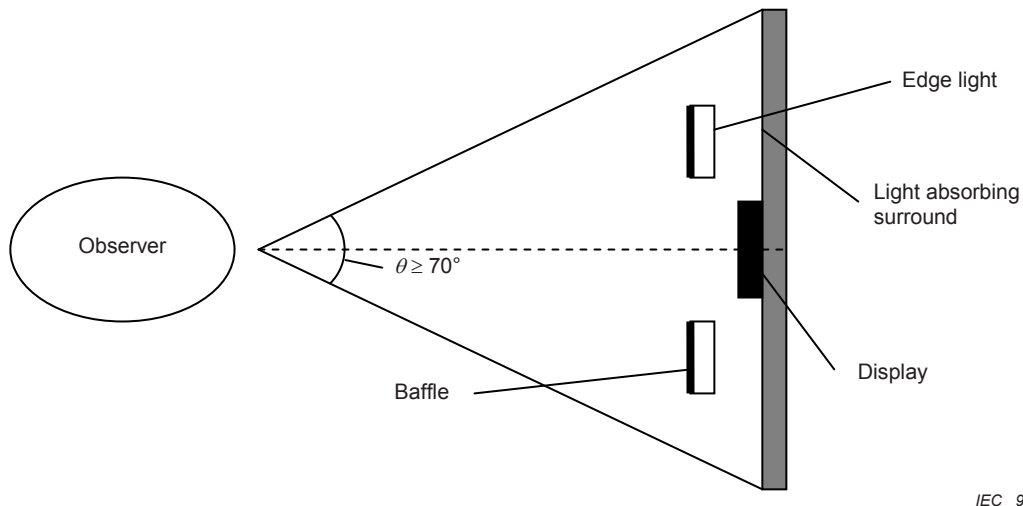
The test patterns to be used for visual inspection shall include full screen patterns with 0 %, 10 % to 30 %, and 100 % grey level depending on application requirements. Test patterns for single colour channels or monochrome displays shall include full screen patterns of all colour subpixels or dots (e.g. red, green, blue, or white) with 0 %, 10 % to 30 %, and 100 % grey level for each respective colour channel depending on application requirements. The grey level of the full screen pattern shall be specified in the detailed specification.

### **6.3.2 Standard inspection method**

#### **6.3.2.1 Set up the inspection equipment and OLED display panels or modules**

DUT will be installed on fixture rotating the horizontal and vertical viewing angle. Turn on direct current power supply and pattern generator. Supply the driving current and pattern to OLED display panel or module as specified for each defect inspection.

The area surrounding the display subtending an angle of 70 ° from the point of the observer shall be made of a light absorbing diffuse material to control ambient light scattering into the visual field of the observer as shown in Figure 12.



**Figure 12 – Setup condition for visual inspection of electro-optical visual defects**

### 6.3.2.2 Inspection method for electro-optic defects

A full screen black test pattern (0 % grey level, display in turned-on state) is applied to inspect for bright subpixel defects.

A full-screen test pattern of between 10 % and 30 % grey level is applied to inspect for mura defects. A grey level of 10 % shall be used unless otherwise specified in the detailed specification. The luminance level shall be recorded in the visual inspection report. Observed defects shall be compared against limit samples.

A test pattern of full screen white (100 % grey level) is applied to inspect for dark subpixel defects.

For colour displays, and if specified in the detailed specification, test patterns for individual colour channels may be applied to inspect for and clarify the nature of subpixel and mura defects.

Observed defects shall be recorded in the visual inspection report.

### 6.3.2.3 Inspection method for mechanical defects

Side illumination of the display using edge lighting (as shown in Figure 12) with an average illuminance of  $> 500$  lx over the display area, measured normal to the display surface over the area of the display, is the preferred condition for inspection of mechanical defects. Inspection of mechanical defects shall be conducted over a wide range of viewing directions. Care shall be taken to block direct viewing of the light source by the inspector.

Two test patterns shall be applied for mechanical defect inspection: a full screen black signal (0 % grey level) to detect visible defects in films and coatings which scatter incident light and a full screen white signal (100 % grey level) to detect mechanical defects that occlude a portion of the display area. For the full screen white pattern, edge lighting shall be turned off.

The inspector shall record observations and classification of mechanical defects in the visual inspection report.



#### **6.3.2.4 Inspector and limit sample for visual inspection**

Inspector shall be periodically trained by a qualified person with a document of specified procedures and limit samples for visual inspection. Limit samples shall be maintained by a qualified person to ensure effectiveness.

#### **6.3.2.5 Inspection and record of result**

Inspector shall record the results of each test in the visual inspection report.

### **6.3.3 Inspection criteria**

#### **6.3.3.1 Bright subpixel defects**

The maximum number of each bright defect shall be specified in specification.

Partial subpixel (any colour) -----Specified in the detail specification

Subpixel (any colour) -----Specified in detail specification

Clustered subpixels -----Specified in detail specification

Total number of bright subpixels ----- Specified in detail specification

#### **6.3.3.2 Dark subpixel defects**

The maximum number of each dark defect shall be specified in specification.

Partial subpixel (any colour) -----Specified in the detail specification

Subpixel (any colour) -----Specified in detail specification

Clustered subpixels -----Specified in detail specification

Total number of dark subpixels -----Specified in detail specification

#### **6.3.3.3 Unstable subpixel**

All kinds of unstable subpixel defects are not allowed.

#### **6.3.3.4 Bright line defect**

All kinds of bright line defects such as vertical, horizontal or cross are not allowed.

#### **6.3.3.5 Dark line defect**

All kinds of dark line defects such as vertical, horizontal or cross are not allowed.

#### **6.3.3.6 Mura**

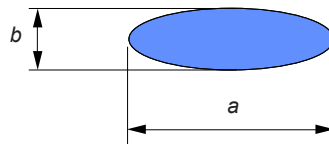
A limit sample providing a variation in luminance or colour representative of various classifications of mura defects provides a reference for acceptable mura defects. The limit sample shall exhibit the same average luminance as the DUT within  $\pm 20\%$ . Colour mura limit samples shall exhibit the same chromaticity coordinates averaged over the display area as the DUT within  $\Delta u'v' < 0,006$  as defined in CIE 15. All kinds of mura defects exceeding the limit sample shall be recorded in the visual inspection report.

#### **6.3.3.7 Mechanical defects**

The scratch, dent, foreign material, and bubble defect criteria are defined in Table 1 and Figure 13. The symbol of "a" and "b" indicates the major and minor axis of the defect.

**Table 1 – Definitions for type of scratch and dent defects**

| Defect   |                            | Criteria  |
|--|----------------------------|---|
| Scratches  | Linear ( $a > 2b$ )        | minimum $\leq$ width [mm] $\leq$ maximum, minimum $\leq$ length [mm] $\leq$ maximum,<br>N(number of defects) $\leq$ maximum |
| Dent   | Elliptical ( $a \leq 2b$ ) | minimum $\leq$ average diameter, $(a+b)/2$ [mm] $\leq$ maximum,<br>N(number of defects) $\leq$ maximum                      |
| Foreign materials  |                            | minimum $\leq$ a(major axis)[mm] $\leq$ maximum,<br>N(number of defects) $\leq$ maximum                                     |
| Bubble   |                            | minimum $\leq$ a(major axis)[mm] $\leq$ maximum,<br>N(number of defects) $\leq$ maximum                                     |
| NOTE 1 Extraneous substances which can be wiped off, like finger prints, particles, etc. are not considered as a defect. |                            |   |
| NOTE 2 Defects which are on the black matrix (outside of Active Area) are not considered defects.                        |                            |   |



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**Figure 13 – Shape of scratch and dent defect**

## 7 Electro-optical measuring methods under ambient illumination

### 7.1 Reflection measurements

#### 7.1.1 Purpose

The purpose of this method is to measure the reflection properties of an OLED display module under defined indoor or daylight illumination conditions. If the OLED exhibits significant PL, the PL will also be incorporated into the reflection coefficient. In that case, this measuring method is still valid when the same illumination spectral distribution is used to calculate the ambient contrast ratio and colour.

#### 7.1.2 Measuring conditions

##### a) Apparatus:

A driving power source; driving signal equipment; integrating sphere, sampling sphere, or hemisphere; and directional light source. For spectral measurements, a spectroradiometer that can measure luminance and spectral radiance is needed; and a white diffuse reflectance standard with known hemispherical diffuse spectral reflectance factor and directed spectral reflectance factor calibrated for the intended measurement geometry. For photometric measurements, a detector is required that can measure luminance; and a white diffuse reflectance standard is required with known luminous hemispherical diffuse reflectance factor and directed reflectance factor calibrated for the intended measurement geometry and source spectra.

##### b) Illuminance condition:

The standard ambient illumination conditions for an indoor room and clear sky daylight shall be used. Additional illumination conditions may also be used, depending on the application.

- c) Except for the standard ambient illumination conditions, all other conditions are the standard conditions.

### 7.1.3 Measuring the hemispherical diffuse reflectance factor

- a) Place the display in an integrating sphere or sampling sphere, as indicated in Figure 2. Turn ON the integrating sphere or sampling sphere hemispherical diffuse illumination to the desired CCT. Allow the light source to stabilize.

NOTE 1 Any change in sphere illuminance can be monitored by a photopic detector attached to the sphere.

- b) Set the test input signal to the display to generate a full white screen (100 % grey level). For natural static image and video applications, a 4 % area window at a 100 % grey level may also be used to characterize the contrast ratio, or a variety of display colours can be measured with the 4 % window to determine the colour gamut. The 4 % window shall be 1/5 the width and height dimensions of the active area, and located in the centre of the display. A contrast ratio measured with a small area window will be referred to as a highlight contrast ratio. The ambient performance report shall note when a highlight measurement is used.
- c) Align the LMD through the measurement port, focused at the centre of the display, and at an 8 ° to 10 ° angle to the display surface normal. Turn room lights OFF. Measure the spectral radiance  $L_{W, \text{hemi-ON}}(\lambda)$  or luminance  $L_{W, \text{hemi-ON}}$  at the centre of the white pattern with the hemispherical surround ON. For spectral measurements, the white display luminance  $L_{W, \text{hemi-ON}}$  can be calculated using Equation (1):

$$L = 683 \int_{\lambda} L(\lambda) V(\lambda) d\lambda \quad (1)$$

where  $V(\lambda)$  is the photopic luminous efficiency function as defined in publication CIE 15.

NOTE 2 In this document, spectral measurements like spectral radiance will be specifically identified by its wavelength dependence (e.g.  $L_{W, \text{hemi-ON}}(\lambda)$ ), whereas its photometric equivalent luminance will have no explicit wavelength dependence (e.g.  $L_{W, \text{hemi-ON}}$ ).

- d) Align the LMD to the centre of the calibrated white diffuse reflectance standard and measure its spectral radiance  $S_{W, \text{hemi-ON}}(\lambda)$  or luminance  $S_{W, \text{hemi-ON}}$  with the hemispherical surround ON and the display in its white state. For the sampling sphere case, the  $S_{W, \text{hemi-ON}}(\lambda)$  or  $S_{W, \text{hemi-ON}}$  is the spectral radiance and luminance, respectively, measured from the sphere wall adjacent to the sample port.
- e) Align the LMD to the centre of the display. Set the display to a 0 % grey level and measure the black screen spectral radiance  $L_{K, \text{hemi-ON}}(\lambda)$  or luminance  $L_{K, \text{hemi-ON}}$  in the centre of the display with the diffuse surround ON.
- f) Align the LMD to the centre of the calibrated white diffuse reflectance standard and measure its spectral radiance  $S_{K, \text{hemi-ON}}(\lambda)$  or luminance  $S_{K, \text{hemi-ON}}$  with the surround ON and the display in its black state.
- g) Turn OFF the integrating sphere or sampling sphere hemispherical diffuse illumination. This may be accomplished by turning off the light source. If the sphere light is input by a portable source (like an optical fibre bundle), then the light can be turned OFF by disconnecting at the light source end so that the interior conditions and performance of the sphere are not changed.
- h) Align the LMD to the centre of the display. Set the display to a 0 % grey level and measure the black screen spectral radiance  $L_{K, \text{hemi-OFF}}(\lambda)$  or luminance  $L_{K, \text{hemi-OFF}}$  in the centre of the display with the diffuse surround OFF.
- i) Align the LMD to the centre of the calibrated white diffuse reflectance standard and measure its spectral radiance  $S_{K, \text{hemi-OFF}}(\lambda)$  or luminance  $S_{K, \text{hemi-OFF}}$  with the surround OFF and the display in its black state.
- j) Align the LMD to the centre of the display. Re-establish the prior white pattern at the 100 % grey level, allow the display emission to stabilize, and measure the white screen

spectral radiance  $L_{W,hemi-OFF}(\lambda)$  or luminance  $L_{W,hemi-OFF}$  in the centre of the display with the diffuse surround OFF.

- k) Align the LMD to the centre of the calibrated white diffuse reflectance standard and measure its spectral radiance  $S_{W,hemi-OFF}(\lambda)$  or luminance  $S_{W,hemi-OFF}$  with the surround OFF and the display in its white state.
- l) Calculate the hemispherical diffuse spectral reflectance factor  $R_{W,hemi}(\lambda)$ , or luminous hemispherical diffuse reflectance  $R_{W,hemi}$ , of the white display pattern at the 100 % grey level for the measured illumination/detection geometry.

For spectral measurements, the following relation is used:

$$R_{W,hemi}(\lambda) = R_{std,hemi}(\lambda) \frac{L_{W,hemi-ON}(\lambda) - L_{W,hemi-OFF}(\lambda)}{S_{W,hemi-ON}(\lambda) - S_{W,hemi-OFF}(\lambda)} \quad (2)$$

where  $R_{std,hemi}(\lambda)$  is the known hemispherical spectral reflectance factor for the white diffuse reflectance standard, or sampling sphere wall, in the same geometry. The luminous hemispherical diffuse reflectance factor  $R_{W,hemi}$  of a display at 100 % grey level at the desired hemispherical diffuse illumination spectra is determined using the spectral reflectance factor  $R_{W,hemi}(\lambda)$  in the following equation:

$$R_{W,hemi} = \frac{\int_{\lambda} R_{W,hemi}(\lambda) E(\lambda) V(\lambda) d\lambda}{\int_{\lambda} E(\lambda) V(\lambda) d\lambda} \quad (3)$$

where  $E(\lambda)$  is the relative spectral distribution of the desired illumination. The spectral distributions of CIE Illuminant A, lamp FL1, D65, D50 and D75 tabulated in CIE 15 shall be used. If additional daylight illuminants are desired, the following relation from CIE 15 shall be used:

$$E(\lambda) = E_0(\lambda) + M_1 E_1(\lambda) + M_2 E_2(\lambda) \quad (4)$$

where the  $E_0$ ,  $E_1$ , and  $E_2$  eigenfunctions are tabulated in CIE 15, and  $M_1$  and  $M_2$  are eigenvalues defined in the same document. For example,  $M_1$  and  $M_2$  are given in Table 2 for the case of D50 and D75.

**Table 2 – Eigenvalues  $M_1$  and  $M_2$  for CIE Daylight Illuminants D50 and D75**

| Eigenvalues | Correlated colour temperature |          |
|-------------|-------------------------------|----------|
|             | 5 000K                        | 7 500K   |
| $M_1$       | -1,0401                       | 0,14358  |
| $M_2$       | 0,36666                       | -0,75993 |

For luminance measurements, the photometric equivalent of Equation (2) is used:

$$R_{W,hemi} = R_{std,hemi} \frac{L_{W,hemi-ON} - L_{W,hemi-OFF}}{S_{W,hemi-ON} - S_{W,hemi-OFF}} \quad (5)$$

However, the luminous hemispherical diffuse reflectance factor  $R_{W,hemi}$  of the display with a white screen, and the white diffuse reflectance standard  $R_{std,hemi}$ , shall only be used for hemispherical diffuse light sources with the same geometry and spectral distribution as that used in this measurement. Therefore, any ambient contrast ratio or colour calculation using the luminous hemispherical diffuse reflectance factor  $R_{W,hemi}$  determined by the photometric method in Equation (5) is only valid for light sources with similar spectra and geometry.

NOTE 3 To ensure measurement integrity, the reflected component of the sphere illumination shall be much greater than the display emission (i.e.  $L_{W,hemi-ON}(\lambda) \gg L_{W,hemi-OFF}(\lambda)$ ). The same applies for the photometric equivalents in Equation (5).

- m) Calculate the hemispherical diffuse spectral reflectance factor  $R_{K,hemi}(\lambda)$ , or luminous hemispherical diffuse reflectance factor  $R_{K,hemi}$ , of the black screen display at the 0 % grey level for the measured illumination/detection geometry.

For spectral measurements, the following relation is used:

$$R_{K,hemi}(\lambda) = R_{std,hemi}(\lambda) \frac{[L_{K,hemi-ON}(\lambda) - L_{K,hemi-OFF}(\lambda)]}{[S_{K,hemi-ON}(\lambda) - S_{K,hemi-OFF}(\lambda)]} \quad (6)$$

The luminous hemispherical diffuse reflectance factor  $R_{K,hemi}$  of a display at 0 % grey level at the desired hemispherical diffuse illumination spectra is determined following the same form as Equations (3) and (4).

For luminance measurements, the photometric equivalent of Equation (6) is used:

$$R_{K,hemi} = R_{std,hemi} \frac{[L_{K,hemi-ON} - L_{K,hemi-OFF}]}{[S_{K,hemi-ON} - S_{K,hemi-OFF}]} \quad (7)$$

When the photometric method is used to determine  $R_{K,hemi}$  via Equation (7), its use in the calculation of ambient contrast is only valid for light sources with similar spectra and geometry as that used in this measurement.

- n) Record the CCT of the display test illumination, the test configuration,  $R_{K,hemi}$ ,  $R_{W,hemi}$ , and the illuminance  $E_{K,hemi-ON}$  on the white diffuse reflectance standard with the display in its black state in the ambient performance report. For spectral measurements, the value of  $E_{K,hemi-ON}$  is determined by using  $S_{K,hemi-ON}(\lambda)$  in the following general equation:

$$E(\lambda) = \frac{\pi S(\lambda)}{R(\lambda)} \quad (8)$$

where  $R(\lambda) = R_{std,hemi}(\lambda)$  in this case.

The illuminance  $E_V$  can be obtained from the spectral irradiance  $E(\lambda)$  by

$$E_V = 683 \int_{\lambda} E(\lambda) V(\lambda) d\lambda \quad (9)$$

For luminance measurements, the illuminance  $E_{K,hemi-ON}$  is obtained by the photometric equivalent of Equation (8) using the white standard luminance  $S_{K,hemi-ON}$ .

The colour temperature, illumination levels, detector parameters (incident angle, measurement field angle, and distance to sample) and illumination source geometry used in the measurements shall be recorded in the ambient performance report.

#### 7.1.4 Measuring the reflectance factor for a directed light source

- a) Align the LMD perpendicular to the display. Measure the spectral radiance  $L_K(\lambda)$  or luminance  $L_K$  in the centre of the display at the 0 % grey level for a full black screen under dark room conditions. For spectral measurements, the black screen luminance  $L_K$  can be calculated using Equation (1).
- b) Set the test input signal to the display to generate a full white screen (100 % grey level). For natural static image and video applications, a 4 % area window at a 100 % grey level may also be used to characterize the highlight contrast ratio. The 4 % window shall be 1/5 the width and height dimensions of the active area, and located in the centre of the display. The ambient performance report shall note when a highlight measurement is used. Measure the spectral radiance  $L_W(\lambda)$ , or luminance  $L_W$ , at the centre of the white pattern

under dark room conditions. For spectral measurements, the white display luminance  $L_W$  can be calculated using Equation (1).

- c) Position the directed source in the geometry defined for indoor or daylight illumination conditions. In general, the isolated directed source geometry shall be used, unless the display exhibits strong matrix scatter. Turn ON the directed light source at the desired CCT, and wait for the light source to stabilize. Adjust the source intensity so that the light reflected off the display produces a strong signal at the LMD. Remove the display and place the white diffuse reflectance standard in the same measurement plane of the LMD.
- d) Measure the spectral radiance  $S_{W,dir}(\lambda)$  or luminance  $S_{W,dir}$  from the calibrated white diffuse reflectance standard. For spectral measurements, the spectral irradiance  $E_{W,dir}(\lambda)$  on the white diffuse reflectance standard and display can be determined by using Equation (8), with  $E(\lambda) = E_{W,dir}(\lambda)$ ,  $S(\lambda) = S_{W,dir}(\lambda)$ , and where  $R(\lambda) = R_{std,dir}(\lambda)$  is the known spectral reflectance factor for the white diffuse reflectance standard in the same geometry. The display illuminance  $E_{W,dir}$  can be calculated using Equation (9). For photometric measurements, an analogous relation to Equation (8) is used to calculate the illuminance  $E_{W,dir}$ .
- e) Replace the display at the LMD measurement plane, and re-establish the prior white pattern at the 100 % grey level. Measure the spectral radiance  $L_{W,dir}(\lambda)$  or the luminance  $L_{W,dir}$  from the centre of the emitting display with directed source illumination ON. For spectral measurements, the luminance  $L_{W,dir}$  from the display with direct illumination can be calculated using Equation (1).

NOTE 1 To ensure measurement integrity, the display ambient spectral radiance with directed source ON will be much greater than the display spectral radiance in a dark room (i.e.  $L_{W,dir}(\lambda) \gg L_W(\lambda)$ ). The same applies for the photometric equivalents.

- f) Calculate the spectral reflectance factor  $R_{W,dir}(\lambda)$ , or luminous reflectance factor  $R_{W,dir}$ , of the white display pattern at the 100 % grey level with directed illumination for the measured illumination/detection geometry.

For spectral measurements, the spectral reflectance factor  $R_{W,dir}(\lambda)$  is determined using the following equation [2]:

$$R_{W,dir}(\lambda) = \pi \frac{L_{W,dir}(\lambda) - L_W(\lambda)}{E_{W,dir}(\lambda)} \quad (10)$$

The following equation shall be used to calculate the luminous reflectance factor  $R_{W,dir}$  for a white display pattern with directional illumination having the desired spectral distribution:

$$R_{W,dir} = \frac{\int R_{W,dir}(\lambda) E(\lambda) V(\lambda) d\lambda}{\int_{\lambda} E(\lambda) V(\lambda) d\lambda} \quad (11)$$

where  $E(\lambda)$  is the relative spectral distribution for the desired illumination spectra. For indoor contrast ratio measurements, the same source spectra shall be used in this calculation as for the hemispherical diffuse reflectance factor (Equation (3)). When calculating the outdoor ambient contrast ratio, CIE Illuminant D50 shall be used for  $E(\lambda)$  following Equation (4).

For photometric measurements, an analogous relation to Equation (10) is used:

$$R_{W,dir} = \pi \frac{L_{W,dir} - L_W}{E_{W,dir}} \quad (12)$$

NOTE 2 The luminous reflectance factor in Equation (12) will only be used to calculate the ambient contrast of the same source spectra and geometry as that used in the measurement.

- g) Set the display to a 0 % grey level and measure the black screen spectral radiance  $L_{K,dir}(\lambda)$  or luminance  $L_{K,dir}$  in the centre of the screen with direct illumination ON. For spectral measurements, the black screen luminance  $L_{K,dir}$  with direct illumination ON can be calculated using Equation (1).
- h) Remove the display and place the white diffuse reflectance standard in the same measurement plane of the LMD. Measure the spectral radiance  $S_{K,dir}(\lambda)$  or luminance  $S_{K,dir}$  from the calibrated white diffuse reflectance standard. The illuminance  $E_{K,dir}$  on the black screen is determined by using Equations (8) and (9). For photometric measurements, the illuminance  $E_{K,dir}$  is determined by using the  $S_K$  measurement with the photometric equivalent of Equation (8).
- i) Calculate the spectral reflectance factor  $R_{K,dir}(\lambda)$ , or luminous reflectance factor  $R_{K,dir}$ , of the white display pattern at the 0 % grey level with directed illumination for the measured illumination/detection geometry.

For spectral measurements, the spectral reflectance factor  $R_{K,dir}(\lambda)$  of the black screen with direct illumination is determined using the following relation:

$$R_{K,dir}(\lambda) = \pi \frac{L_{K,dir}(\lambda) - L_K(\lambda)}{E_{K,dir}(\lambda)} \quad (13)$$

The luminous reflectance factor  $R_{K,dir}$  for a black field display with directional illumination having the desired spectral distribution  $E(\lambda)$  shall be calculated following the method in Equation (11).

For photometric measurements, the analogous relation to Equation (12) is used to determine the reflectance factor of the black screen  $R_{K,dir}$ .

NOTE 3 The luminous reflectance factor  $R_{K,dir}$  determined through photometric measurements will only be used to calculate the ambient contrast of the same source spectra and geometry as that used in the measurement.

- j) Record the CCT of the display test illumination, the test configuration,  $R_{W,dir}$ ,  $R_{K,dir}$ , and the measured illumination level  $E_{K,dir}$  in the ambient performance report.

The colour temperature, illumination levels, detector parameters (incident angle, measurement field angle, distance to sample) and illumination source parameters (incident angle, angular subtense, distance to sample, beam divergence) used in the measurements shall be recorded in the ambient performance report.

## 7.2 Ambient contrast ratio

### 7.2.1 Purpose

The purpose of this method is to determine the ambient contrast ratio of an OLED display module under defined indoor or daylight illumination conditions.

NOTE If the OLED exhibits significant PL, then the ambient contrast ratio calculation is only valid for the same illumination spectra and geometry used to measure the reflection coefficients.

### 7.2.2 Measuring conditions

- a) Apparatus:

A luminance meter or spectroradiometer that can measure luminance; driving power source; and driving signal equipment.

- b) Illuminance condition:

The standard ambient illumination conditions for an indoor room or clear sky daylight shall be used. Additional illumination conditions may also be used, depending on the application.

- c) Except for the standard ambient illumination conditions, all other conditions are the standard conditions.

### 7.2.3 Measuring method

The ambient contrast ratio is determined from reflection measurements of the display under hemispherical diffuse and directed source illumination conditions [2]. The measuring method for hemispherical diffuse reflectance factor and directed reflectance factor of the display for the required illumination spectra is defined in the previous sections. These reflection parameters are used to calculate the combined (emitted and reflected) luminance of a display with a black screen and white screen at the required illuminance levels. The ambient contrast ratio is the ratio of the combined white screen luminance to the combined black screen luminance.

Measure the black luminance  $L_K$  at the centre and perpendicular to the display at a 0 % grey level for a full black screen under dark room conditions. Set the test input signal to the display to generate a 100 % grey level over the full screen or 4 % window located in the centre of the display (depending on the intended application). Measure the white luminance  $L_W$  at the centre and perpendicular to the white display pattern under dark room conditions. Calculate the indoor room or daylight contrast ratio of a full white screen, or the highlight ambient contrast ratio with a 4 % window, using the following equation [2]:

$$ACR = \frac{\left( L_W + \frac{R_{W,hemi} E_{hemi}}{\pi} + \frac{R_{W,dir} E_{dir} \cos \theta_s}{\pi} \right)}{\left( L_K + \frac{R_{K,hemi} E_{hemi}}{\pi} + \frac{R_{K,dir} E_{dir} \cos \theta_s}{\pi} \right)} \quad (14)$$

where the default parameters are  $E_{hemi} = 60$  lx,  $\theta_s = 35^\circ$ , and  $E_{dir} \cos \theta_s = 40$  lx for a TV viewing room;  $E_{hemi} = 300$  lx,  $\theta_s = 35^\circ$ , and  $E_{dir} \cos \theta_s = 200$  lx for an office; and  $E_{hemi} = 15\,000$  lx,  $\theta_s = 45^\circ$ , and  $E_{dir} \cos \theta_s = 65\,000$  lx for the outdoor daylight contrast ratio. If additional geometries or illuminance levels are used, they shall be noted in the ambient performance report. All values used to calculate the ambient contrast ratio shall be recorded in the ambient performance report.

## 7.3 Ambient display colour

### 7.3.1 Purpose

The purpose of this method is to measure the ambient colour of an OLED display module under defined daylight illumination conditions.

NOTE If the OLED exhibits significant PL, then the ambient display colour calculation is only valid for the same illumination spectra and geometry used to measure the reflection coefficients.

### 7.3.2 Measuring conditions

a) Apparatus:

A spectroradiometer that can measure spectral radiance; driving power source; and driving signal equipment.

b) Illuminance condition:

The standard ambient illumination conditions for clear sky daylight shall be used. Additional illumination conditions may also be used, depending on the application.

c) Except for the standard ambient illumination conditions, all other conditions are the standard conditions.

### 7.3.3 Measuring method

The chromaticity of a display under hemispherical diffuse and directed illumination conditions is a combination of the display's intrinsic light emission and reflected ambient light. The ambient chromaticity of a display at a given colour state (e.g. white, black, red, green, or blue



screen) under illumination conditions is determined by its equivalent ambient tristimulus values. These values can be obtained from dark room measurements at the desired colour state, and reflection measurements of the display under hemispherical diffuse and directed source illumination conditions at that colour. The measuring methods for the hemispherical diffuse spectral reflectance factor and directed spectral reflectance factor of the display are described in previous sections.

Measure the spectral radiance  $L_Q(\lambda)$  at the centre and perpendicular to the display at the desired colour state Q (e.g. white screen) under dark room conditions. The total ambient spectral radiance  $L_{Q,amb}(\lambda)$  measured by a detector perpendicular to the display, with reflections from the hemispherical diffuse and directional sources included, will be:

$$L_{Q,amb}(\lambda) = L_Q(\lambda) + \frac{R_{Q,hemi}(\lambda)E_{hemi}(\lambda)}{\pi} + \frac{R_{Q,dir}(\lambda)E_{dir}(\lambda)\cos\theta_s}{\pi} \quad (15)$$

where  $E_{hemi}$  and  $E_{dir}$  are the irradiance spectra for the standard hemispherical diffuse and directed sources, respectively. The relative irradiance spectra of CIE Illuminants D75 and D50 for daylight illumination are defined by Equation (4) and Table 2.  $E_{hemi}(\lambda)$  and  $E_{dir}(\lambda)$  are obtained by multiplying the relative spectra by an appropriate constant that would produce the default illumination levels are  $E_{hemi} = 15000$  lx and  $E_{dir}\cos\theta_s = 65000$  lx at  $\theta_s = 45^\circ$  for outdoor daylight under clear sky conditions when integrated using Equation (9). The effective ambient tristimulus values of the display under these illumination conditions are:

$$X_{Q,amb} = 683 \int_{\lambda} L_{Q,amb}(\lambda) \bar{x}(\lambda) d\lambda \quad (16)$$

$$Y_{Q,amb} = 683 \int_{\lambda} L_{Q,amb}(\lambda) \bar{y}(\lambda) d\lambda \quad (17)$$

$$Z_{Q,amb} = 683 \int_{\lambda} L_{Q,amb}(\lambda) \bar{z}(\lambda) d\lambda \quad (18)$$

where  $\bar{x}(\lambda)$ ,  $\bar{y}(\lambda)$ , and  $\bar{z}(\lambda)$  are the colour matching functions (see CIE 15). The ambient 1931 CIE x and y chromaticity coordinates of the emitting display at the desired colour state Q under the defined ambient illumination conditions are:

$$x_Q = \frac{X_{Q,amb}}{X_{Q,amb} + Y_{Q,amb} + Z_{Q,amb}} \quad (19)$$

$$y_Q = \frac{Y_{Q,amb}}{X_{Q,amb} + Y_{Q,amb} + Z_{Q,amb}} \quad (20)$$

## 7.4 Ambient colour gamut volume

### 7.4.1 Purpose

The purpose of this method is to measure the ambient colour gamut volume of an OLED display module under defined daylight illumination conditions. This colour gamut volume shall be compared to the IEC sRGB standard (IEC 61966-2-1) colour gamut volume with a D65 white point. This method is limited to OLED display modules with RGB primaries.

NOTE If the OLED exhibits significant PL, then the ambient colour gamut volume calculation is only valid for the same illumination spectra and geometry used to measure the reflection coefficients.

#### 7.4.2 Measuring conditions

a) Apparatus:

A spectroradiometer that can measure spectral radiance; driving power source; and driving signal equipment. The signal equipment shall be used to deliver the appropriate analog or digital output signal to the OLED display module in order to produce the required colour test pattern.

b) Illuminance condition:

The standard ambient illumination conditions for clear sky daylight shall be used (see 5.2.2.2). Additional illumination conditions may also be used, depending on the application.

c) Except for the standard ambient illumination conditions, all other conditions are the standard conditions.

#### 7.4.3 Measuring method

The ambient colour gamut volume will be calculated from the reflectance factor and tristimulus values measured for each displayed colour following the procedures in the previous sections. The measurements and calculations shall be consistently performed for a 4 % box window colour on a black background.

The ambient colour gamut will be represented by the span of display colours under the defined ambient lighting conditions contained within the measured CIELAB colour space. The volume of that colour space under ambient display illumination is determined by the following procedure:

- a) Apply a 4 % box window pattern, for at least 8 defined colours. The colours shall uniformly sample the display's colour capability. For example, a 3-primary display shall be measured for at least red, green, blue, cyan, yellow, magenta, black and 100 % grey level white (see Table 3). Each colour (except black) is displayed at its maximum signal level.
- b) The dark room spectral radiance and spectral reflectance factor shall be measured for each display colour, as discussed in the previous sections. If it can be shown that the spectral reflectance factor is invariant to the displayed colour at maximum signal level, then a common hemispherical diffuse or directional spectral reflectance factor can be used for all the colours at maximum signal level. The ambient tristimulus values for each display colour under the desired illumination conditions are calculated using Equations (16) to (18).

**Table 3 – Example of minimum colours required for gamut volume calculation of a 3-primary 8-bit display**

| Colour  | 8-bit Signal Level (V)          |
|---------|---------------------------------|
| Red     | Red= 255, Green= 0, Blue= 0     |
| Green   | Red= 0, Green= 255, Blue= 0     |
| Blue    | Red= 0, Green= 0, Blue= 255     |
| Yellow  | Red= 255, Green= 255, Blue= 0   |
| Magenta | Red= 255, Green= 0, Blue= 255   |
| Cyan    | Red= 0, Green= 255, Blue= 255   |
| White   | Red= 255, Green= 255, Blue= 255 |
| Black   | Red= 0, Green= 0, Blue= 0       |

- c) The normalized ambient tristimulus values which are calculated for all defined display colours and signal levels shall be transformed into the three-dimensional, CIELAB colour space (see publication CIE 15). Additional three-dimensional uniform colour spaces may also be used, and identified in the ambient performance report. Each colour point can be

plotted on the  $L^*$ ,  $a^*$ , and  $b^*$  axes of the CIELAB colour space by referencing the peak white ambient tristimulus values ( $X_{W,amb}$ ,  $Y_{W,amb}$  and  $Z_{W,amb}$ ) and using the following transformation equations:

$$L^* = 116 \times f(Y_{Q,amb} / Y_{W,amb}) - 16 \quad (21)$$

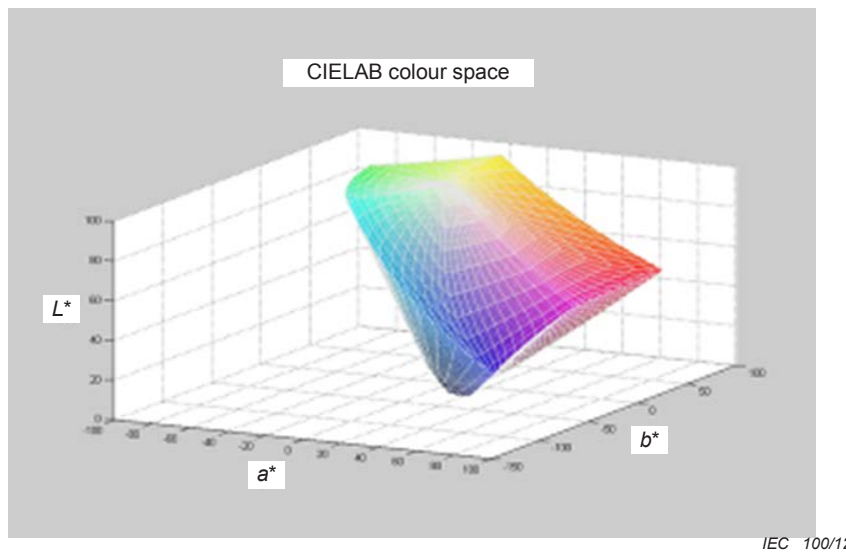
$$a^* = 500 \times [f(X_{Q,amb} / X_{W,amb}) - f(Y_{Q,amb} / Y_{W,amb})] \quad (22)$$

$$b^* = 200 \times [f(Y_{Q,amb} / Y_{W,amb}) - f(Z_{Q,amb} / Z_{W,amb})] \quad (23)$$

where

$$f(t) = \begin{cases} t^{1/3} & t > (6/29)^3 \\ \frac{1}{3} \left(\frac{29}{6}\right)^2 t + \frac{16}{116} & \text{otherwise} \end{cases} \quad (24)$$

An example of the ambient colour data in the CIELAB uniform colour space is given in Figure 14.



**Figure 14 – An example of range in colours produced by a given display as represented by the CIELAB colour space**

- d) Calculate the colour gamut volume corresponding to the possible range of ambient display colours as represented in the CIELAB colour space. See Annex B for a detailed description of the analysis recommended to calculate the colour gamut volume. Other gamut calculation methods may be used if they yield the same results as the reference method described in Annex B.

#### 7.4.4 Reporting

The CIELAB colour gamut volume shall be reported in the ambient performance report along with the characteristics of the ambient illumination that were used. If additional colour spaces are used, they shall be reported as well. Report the spectral reflectance factors. The measured ambient tristimulus values shall all be reported as illustrated in Table 4. Table 4 shall indicate the original effective tristimulus values, i.e., shall not be normalized to 100. For each ambient illumination condition, a separate table is required. The CCT and white point, obtained by applying Equations (19) and (20) in the darkened room and ambient condition,

shall be reported in Table 5. The percent of colour gamut volume relative to the IEC sRGB standard colour space (IEC 61966-2-1) with a D65 white point shall be reported in a form described by Table 6.

**Table 4 – Measured tristimulus values for the minimum set of colours (see Table 3) required for gamut volume calculation under the specified ambient illumination condition**

| Colour  | $X_{Q,amb}$ | $Y_{Q,amb}$ | $Z_{Q,amb}$ |
|---------|-------------|-------------|-------------|
| Red     |             |             |             |
| Green   |             |             |             |
| Blue    |             |             |             |
| Yellow  |             |             |             |
| Magenta |             |             |             |
| Cyan    |             |             |             |
| White   |             |             |             |
| Black   |             |             |             |

**Table 5 – Calculated white point in the darkened room and ambient condition**

| Colour | Surround          | $x$ | $y$ | CCT |
|--------|-------------------|-----|-----|-----|
| White  | Dark room         |     |     |     |
|        | Ambient condition |     |     |     |

**Table 6 – Colour gamut volume in the CIELAB colour space**

| Colour Gamut Volume  |   |
|----------------------|---|
| Ambient illumination | Percent relative to sRGB ( $8,20 \times 10^5$ ) |
| Dark room            | %   |
| Clear sky daylight   | %   |

## Annex A (informative)

### Measuring relative photoluminescence contribution from displays

#### A.1 Purpose

The purpose of this method is to estimate the relative amount of PL emitted by a display under illumination relative to the reflected component.

#### A.2 Measuring conditions

a) Apparatus:

A spectroradiometer that can measure spectral radiance over at least the 380 nm to 780 nm wavelength range; a spectrally tunable unpolarized light source capable of producing light from at least 380 nm to 780 nm. The tunable light source and detector shall be stable to < 1 % over the time period of the measurement. The spectral bandwidth of the detector and light source shall not exceed 10 nm. The spectral bandwidth of the spectroradiometer shall be an integer multiple of the sampling interval.

b) Illuminance condition:

The standard ambient illumination conditions for clear sky daylight shall be used. The PL is assumed to be linear over the illuminance range of interest. Therefore, any illumination levels that provide a strong signal may be used. However, the results are only valid for the spectral distribution used in this measurement.

c) Except for the defined illumination sources, the measurements will be performed in a dark room with the display in the OFF or black state.

#### A.3 Measuring the bi-spectral photoluminescence of the display

a) Place the display to be measured in the hemispherical diffuse or directional illumination geometry of interest (as defined in Clause 5). For simulating the affect of PL under standard daylight illumination, the directional source geometry is recommended as an initial test case.

b) The spectroradiometer shall be focused on the display surface and centred on the active area.

c) The tunable light source shall produce uniform illumination (within  $\pm 5\%$ ) over the measurement field area of the display.

d) The spectroradiometer shall measure the spectral radiance  $L(\lambda, \lambda_{\text{ex}})$  for monochromatic source illumination  $E_0(\lambda_{\text{ex}})$  at each wavelength  $\lambda_{\text{ex}}$ .

e) Replace the display with a white diffuse reflection standard with known spectral reflectance factor  $R_{\text{std}}(\lambda_{\text{ex}})$  for the illumination/detection geometry used. The reflection standard used shall not exhibit any PL over the wavelength range of interest.

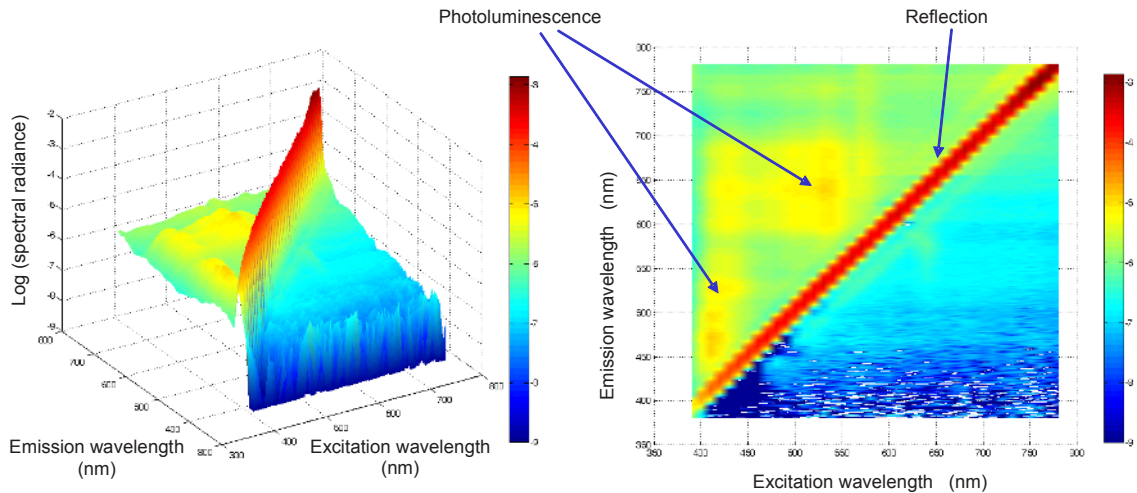
f) The spectroradiometer shall measure the reflected spectral radiance  $S(\lambda, \lambda_{\text{ex}})$  for monochromatic source illumination  $E_0(\lambda_{\text{ex}})$  at each wavelength  $\lambda_{\text{ex}}$ .

#### A.4 Determining relative PL contribution from display

a) The spectral radiance  $L_E(\lambda, \lambda_{\text{ex}})$  of the display spectra under the desired reference spectral irradiance  $E(\lambda_{\text{ex}})$  at the same illumination/detection geometry can be calculated from the measured spectral radiance  $L(\lambda, \lambda_{\text{ex}})$  at each illumination wavelength  $\lambda_{\text{ex}}$  using the relation below:

$$L_E(\lambda, \lambda_{ex}) = L(\lambda, \lambda_{ex}) \frac{E(\lambda_{ex}) R_{std}(\lambda_{ex})}{\pi S(\lambda_{ex}, \lambda_{ex})} \quad (\text{A.1})$$

An example of the three dimensional representation of the scaled bi-spectral display response is given in Figure A.1.

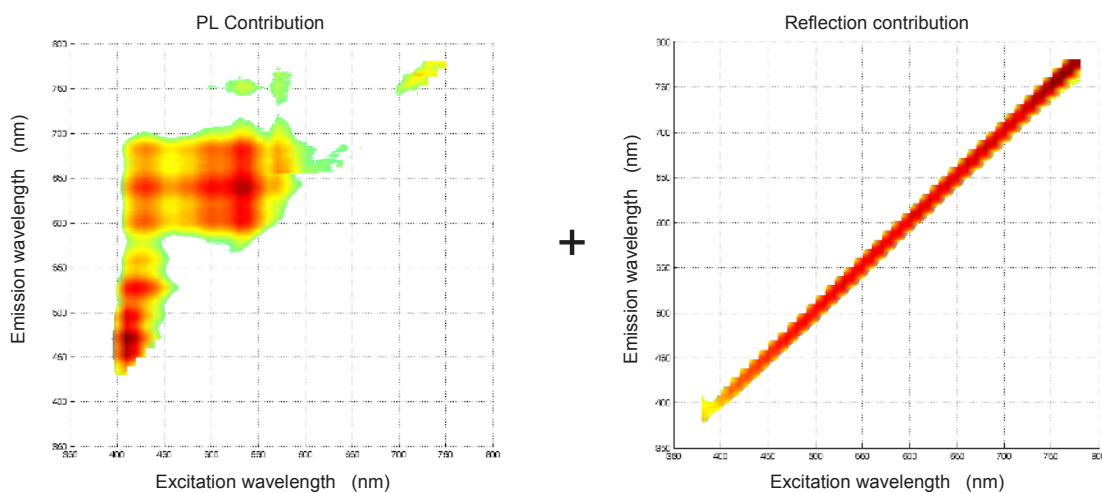


IEC 101/12

**Figure A.1 – Scaled bi-spectral photoluminescence response from a display**

The pure reflection signal does not exhibit a wavelength shift, and is represented by the red diagonal peak in Figure A.1. Since the PL will always be emitted at wavelengths longer than  $\lambda_{ex}$ , the PL contributions are confined to the upper diagonal elements in Figure A.1.

- b) The relative contribution of the PL can be estimated by decomposing the data in Figure A.1 into its PL component (the upper diagonal) and the reflection component (the peak along the diagonal) as shown in Figure A.2. The background noise shall be subtracted to improve the accuracy of the analysis.



IEC 102/12

**Figure A.2 – Decomposed bi-spectral photoluminescence response from a display**

- c) If the display was illuminated with the entire illumination spectra  $E(\lambda_{ex})$  at once, then the radiance contribution for the PL and reflected components can be calculated by integrating over the row elements in Figure A.2:

$$L_{PL}(\lambda) = \sum_{\lambda_{ex}} L_{PL,E}(\lambda, \lambda_{ex}) \quad \text{for } \lambda > \lambda_{ex} + \Delta\lambda / 2 \quad (\text{A.2})$$

and

$$L_{Refl}(\lambda) = \sum_{\lambda_{ex}} L_{Refl,E}(\lambda, \lambda_{ex}) \quad \text{for } \lambda \leq (\lambda_{ex} + \Delta\lambda/2) \text{ to } \lambda \geq (\lambda_{ex} - \Delta\lambda/2) \quad (\text{A.3})$$

where  $\Delta\lambda$  is the bandwidth of the spectral radiance reflection peak at each  $\lambda_{ex}$ .

- d) The photopically-weighted contribution of the PL ( $L_{PL}$ ) and reflected ( $L_{Refl}$ ) components can be calculated by applying the results from Equations (A.2) and (A.3), and using Equation (1).
- e) The photopically-weighted contribution of the PL component relative to the total can then be expressed by the ratio:

$$\frac{L_{PL}}{L_{PL} + L_{Refl}} \quad (\text{A.4})$$

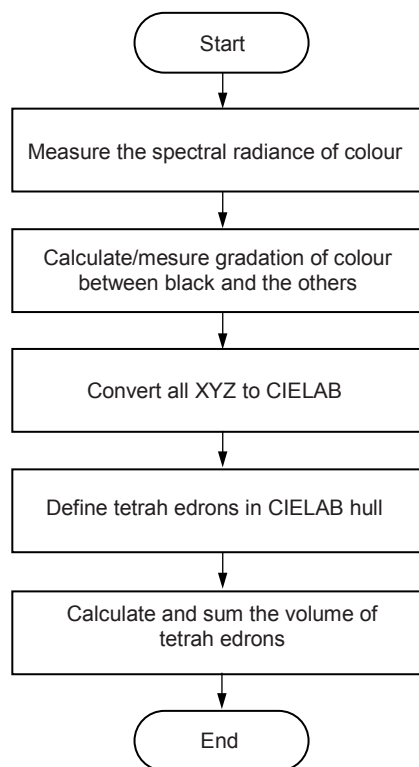
## Annex B (informative)

### Calculation method of ambient colour gamut volume

#### B.1 Purpose

The purpose of this method is to describe a procedure to calculate the colour gamut volume of scattered colour points in the three-dimensional CIELAB colour space.

#### B.2 Procedure for calculating the colour gamut volume



IEC 103/12

**Figure B.1 – Analysis flow chart for calculating the colour gamut volume**

Measure at least the red, green, blue, cyan, magenta, yellow, black and white colours of the display under the defined ambient conditions according to 7.4.3. Table B.1 provides an example using sRGB primaries, under dark room illumination conditions and with the white luminance (Y) normalized to 100( %):



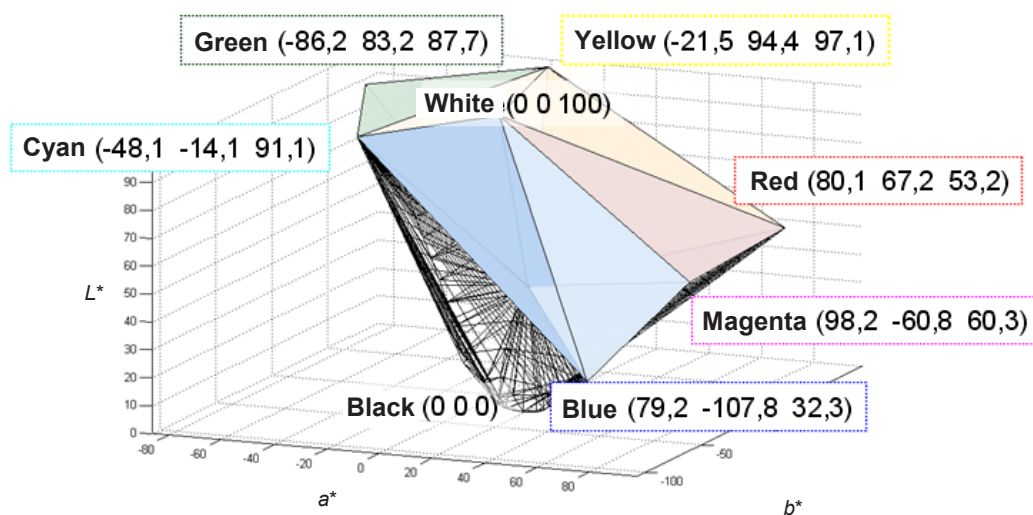
**Table B.1 – Tristimulus values of the sRGB primary colours**

| Colour  | $x_Q$  | $y_Q$  | $X_{Q,amb}$ | $Y_{Q,amb}$ | $Z_{Q,amb}$ |
|---------|--------|--------|-------------|-------------|-------------|
| Red     | 0,640  | 0,330  | 41,239      | 21,264      | 1,933       |
| Green   | 0,300  | 0,600  | 35,758      | 71,517      | 11,919      |
| Blue    | 0,150  | 0,060  | 18,048      | 7,219       | 95,053      |
| Cyan    | 0,225  | 0,329  | 53,806      | 78,736      | 106,973     |
| Magenta | 0,321  | 0,154  | 59,287      | 28,483      | 96,986      |
| Yellow  | 0,419  | 0,505  | 76,998      | 92,781      | 13,853      |
| Black   | 0      | 0      | 0,000       | 0,000       | 0,000       |
| White   | 0,3127 | 0,3290 | 95,046      | 100,000     | 108,906     |

Convert all colours points into the CIELAB colour space using Equations (21) to (23). See Table B.2 and Figure B.2 for an example of the sRGB colour set in the CIELAB colour space.

**Table B.2 – Example of sRGB colour set represented in the CIELAB colour space**

| Colour  | $a^*$    | $b^*$     | $L^*$   |
|---------|----------|-----------|---------|
| Red     | 80,1053  | 67,2227   | 53,2328 |
| Green   | -86,1884 | 83,1861   | 87,7370 |
| Blue    | 79,1936  | -107,8537 | 32,3025 |
| Cyan    | -48,0839 | -14,1278  | 91,1165 |
| Magenta | 98,2497  | -60,8329  | 60,3199 |
| Yellow  | -21,5608 | 94,4877   | 97,1382 |
| Black   | 0        | 0         | 0       |
| White   | 0        | 0         | 100     |



**Figure B.2 – Graphical representation of the colour gamut volume for sRGB in the CIELAB colour space**

Compute the colour gamut volume by adding up all the tetrahedrons contained within the displayed colour points and report as a percentage of the volume compared with sRGB colour gamut volume. An example of a display in a dark room with the sRGB colour gamut volume calculated in the CIELAB colour space is provided in Table B.3.

**Table B.3 – Example of sRGB colour gamut volume in the CIELAB colour space**

| Colour Gamut Volume      |                    |
|--------------------------|--------------------|
| Total                    | $8,20 \times 10^5$ |
| Percent relative to sRGB | 100 %              |

### B.3 Surface subdivision method for CIELAB gamut volume calculation

#### B.3.1 Purpose

This algorithm accepts an arbitrary set of gamut corner cases specified in CIE 1931 XYZ tristimulus values. The minimum set of colours would be red, green, blue, cyan, magenta, yellow, black and white. The XYZ values are arranged in the rows of the input variable *P*, with a minimum eight colour corner cases required. The output value is the calculated colour gamut volume.

#### B.3.2 Assumptions

It is assumed that the colour gamut in CIE XYZ colour space will be defined as the convex hull of given corner cases. The colour gamut in CIELAB colour space will be this convex hull, normalised in CIE XYZ space by the corner case with the maximum luminance (taken as the white point), and translated into CIELAB colour space where it will no longer be entirely convex.

#### B.3.3 Algorithm

- 1) Obtain the convex hull<sup>2</sup> of the colour corner points in *P*. Store the tessellation of the surface of this hull in *T*. Initialise a total volume *v* to 0.
- 2) Calculate the average of the points *P* to be used as a gamut mid-point and store in *P<sub>m</sub>*.
- 3) For each triangular surface tile in *T*
  - a) Let *s* equal the number of edges that have extents<sup>3</sup> in *L\**, *a\**, *b\** coordinates greater than 10.
  - b) If *s* = 0 then calculate the volume defined between the vertices of the surface tile and *P<sub>m</sub>*. Add this volume to *v*.
  - c) If *s* = 3 then calculate the mid-points in CIEXYZ space and subdivide the triangular tile into 4 sub-tiles defined by each corner vertex with the two nearest mid-points and the three mid-points. Repeat 3 for each triangular sub-tile.
  - d) If *s* = 1 or 2 then calculate the mid-point in CIEXYZ space of the edge with the largest extents in CIELAB and subdivide the triangular tile into two sub-tiles along the line between the mid-point and opposite vertex. Repeat 3 for each triangular sub-tile.
- 4) Return the total volume now contained in *v*.

<sup>2</sup> Where the corner points are the standard RGBCMYKW.

<sup>3</sup> Extents are used rather than length as they are faster to calculate.

CIELabVol\_subd.m

```

function [v] = CIELabVol_subd(P)
%Each row of P contains XYZ tri-stimulus values of gamut corner points.
%The 3D gamut is defined as the convex hull of these points in XYZ space.
%The surface is recursively subdivided down to a threshold scale in CIELAB
%and the volume made by each surface tile to a central point is summed

thresh=10; %CIELab subdivision threshold

%Get the hull defined by the points
T=convhulln(P);

%Get the white point (taken as the primary with the maximum Y)
[W,i]=max(P(:,2));
W=P(i,:);

%Normalise the gamut to the white point
Pn=P./(repmat(W,size(P,1),1));

%get the mid-point
Pm=mean(Pn);

%add-on the CIELab points
Pn=[Pn, XYZ2Lab(Pn)];
Pm=[Pm, XYZ2Lab(Pm)];

%calculate and sum the Lab volume of each surface tile to the mid-point
v=0;
for n=1:size(T,1),
    v=v+SubDLabVol(Pn(T(n,:),:),Pm,thresh);
end

%% sub-functions
% XYZ2Lab converts XYZ values arranged in columns to L* a* b*
function [ t ] = XYZ2Lab( t )
    i=(t>0.008856);
    t(i)=t(i).^(1/3);
    t(~i)=7.787*t(~i)+16/116;
    t=[116*t(:,2)-16, 500*(t(:,1)-t(:,2)), 200*(t(:,2)-t(:,3))];
end

%Recursive function to divide up the surface tile then return the volume
function [ v ] = SubDLabVol( vp,c,th )
    %Get the max extent of each edge (quicker than length calculation)
    m=max(abs(vp-circshift(vp,1)),[],2);
    %Count how many edges have extents larger than the threshold
    s=sum(m>th);

    if (s==0), %no edges larger: return the volume
        v=abs(det(vp(:,4:6) - repmat(c(1,4:6),3,1)))/6);
    elseif (s==3),%all edges larger: divide tile in four
        %get edge mid-points
        ip=(vp(:,1:3)+circshift(vp(:,1:3),1))/2;

        %calculate CIELab points of the mid-points
        ip=[ip,XYZ2Lab(ip)];
    end
end

```

```

%and call recursively for each sub-tile
v=SubDLabVol([vp(1,:);ip(1:2,:)],c,th);
v=v+SubDLabVol([vp(2,:);ip(2:3,:)],c,th);
v=v+SubDLabVol([vp(3,:);ip(1:2:3,:)],c,th);
v=v+SubDLabVol(ip,c,th);

else %one or two edges larger: split the tile on the largest edge
%shift the order so 1-2 has the largest extent
[m,i]=max(m);
vp=circshift(vp,2-i);

%calculate the mid-point of 1-2 and the CIE Lab point
ip=(vp(1,1:3)+vp(2,1:3))/2;
ip=[ip,XYZ2Lab(ip)];

%and call recursively for the two sub-tiles
v=SubDLabVol([vp([1 3],:);ip],c,th);
v=v+SubDLabVol([vp(2:3,:);ip],c,th);
end
end
end

```

```

GetGamutCorners.m

function [ P ] = GetGamutCorners( P ,wh)
%GET PRIM returns a set of colour corner points based on a standard gamut
% input string must contain one of:
% 'sRGB', 'Rec709', 'EBU', 'NTSC'
% optionally one of
% 'D50', 'D55', 'D65', 'D75', 'IIIA', 'IIIE'
if ischar(P)
if nargin<2
wh=P;
end
if strfind(P,'sRGB') || strfind(P,'Rec709')
prim=[0.64,0.33;0.3,0.6;0.15,0.06];
elseif strfind(P,'EBU')
prim=[0.64,0.33;0.29,0.6;0.15,0.06];
elseif strfind(P,'NTSC')
prim=[0.67,0.33;0.21,0.71;0.14,0.08];
else
error('non-valid colour primary specification');
end
P=prim;
end
if ischar(wh)
if strfind(wh,'D50')
wh=[0.3457,0.3585];
elseif strfind(wh,'D55')
wh=[0.3324,0.3474];
elseif strfind(wh,'D65')
wh=[0.3127,0.3290];
elseif strfind(wh,'D75')
wh=[0.2990,0.3149];

```

```
elseif strfind(wh,'IIIA')
    wh=[0.44757,0.40745];
elseif strfind(wh,'IIIE')
    wh=[0.3333,0.3333];
else
    wh=[0.3127,0.3290];
    display('Default D65 white used');
end
end
wh=[wh, 1-sum(wh)]/wh(2);
P=[P, 1-sum(P,2)];
P=P.*repmat((wh/P)',1,3);
%P=[KRYGCBMW]
P=[0 0 0;P(1,:);sum(P(1:2,:));P(2,:);sum(P(2:3,:));...
    P(3,:);sum(P([1 3],:)); sum(P)];
end
```

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